The image is a false-color plot representing the intensity of an ARPES experiment. The background is dark blue. A prominent feature is a bright, elongated, and somewhat curved structure on the left side, colored in yellow, orange, and red, indicating high intensity. This structure appears to be a surface state or a bulk band edge. A vertical dashed white line is drawn through the center of the plot, likely representing a high-symmetry direction in the Brillouin zone. The overall appearance is that of a Fermi surface map or a band structure plot.

***Bulk and surface  
electronic properties  
of  $RERh_2Si_2$  compounds  
( $RE$  = rare-earth element)  
as observed by ARPES***

C. Laubschat,  
Technische Universität Dresden,  
Germany

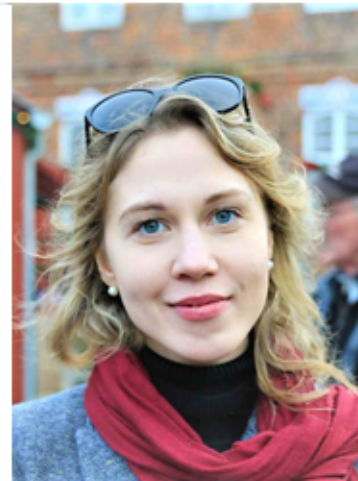
# Acknowledgement:



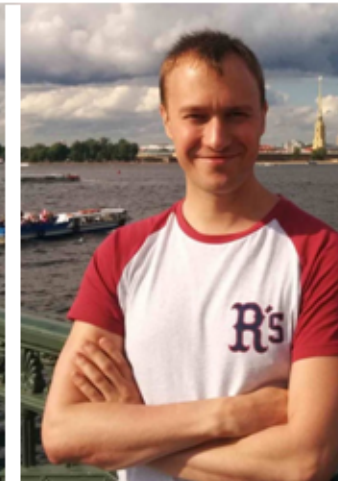
**Denis  
Vyalikh**  
**San Sebastian**



**Monika  
Güttler**



**Alla  
Chikina**  
**SLS**



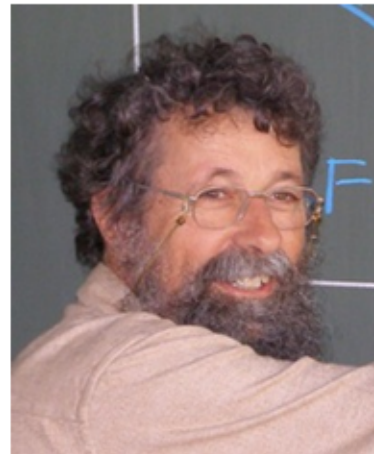
**Alexander  
Generalov**  
**Max / Lund**



**Marc  
Höppner**  
**MPI Stuttgart**



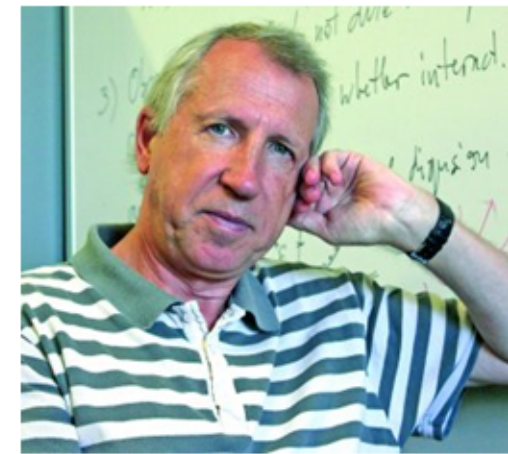
**Kurt  
Kummer**  
**ESRF**



**Christoph  
Geibel**  
**MPI CPfS Dresden**

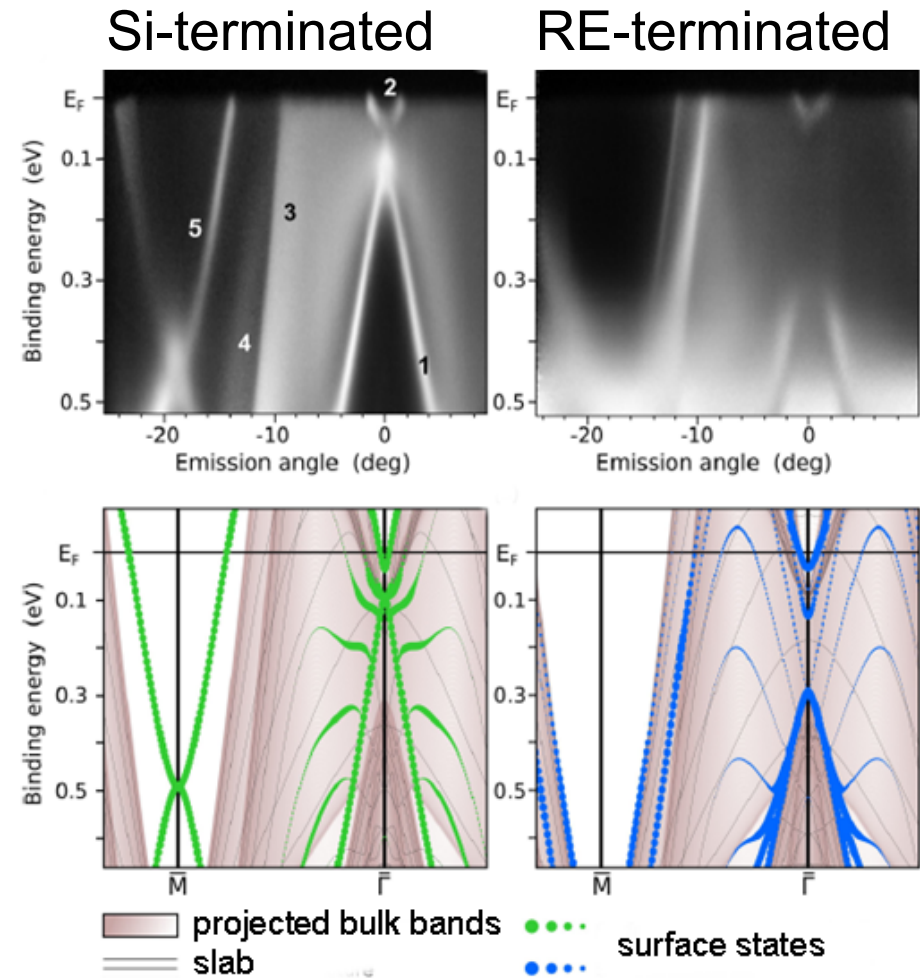
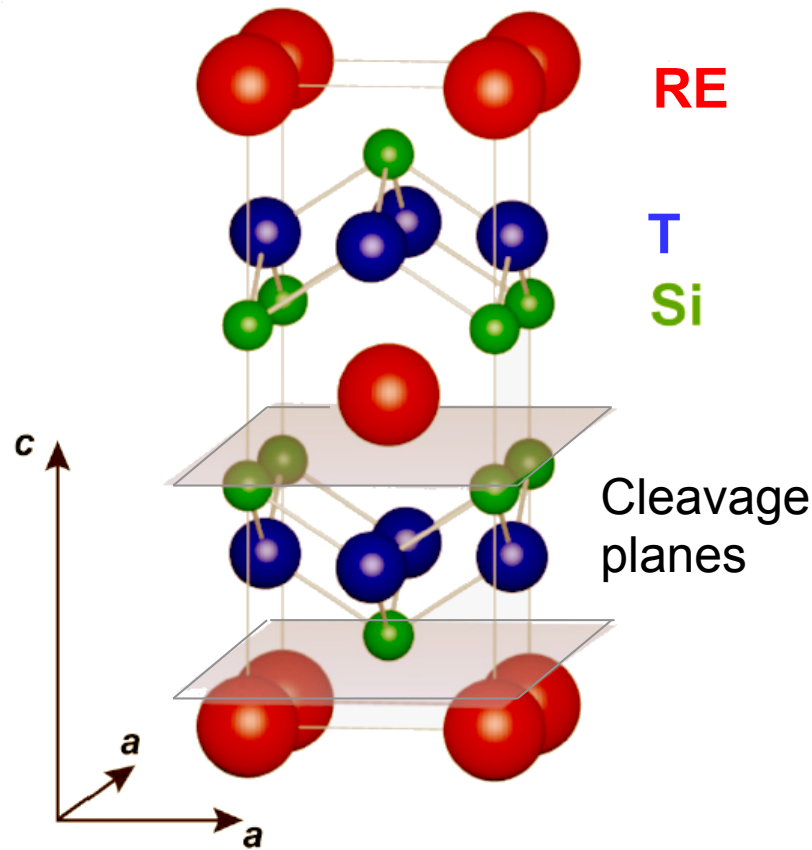


**Cornelius  
Krellner**  
**Frankfurt**



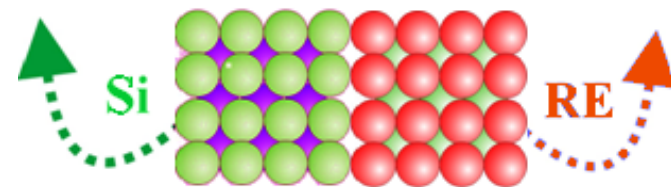
**Eugeny  
Chulkov**  
**San Sebastian**

# $RET_2Si_2$ compounds ( $RE = \text{rare-earth}, T = \text{Co, Rh, Ir}$ )



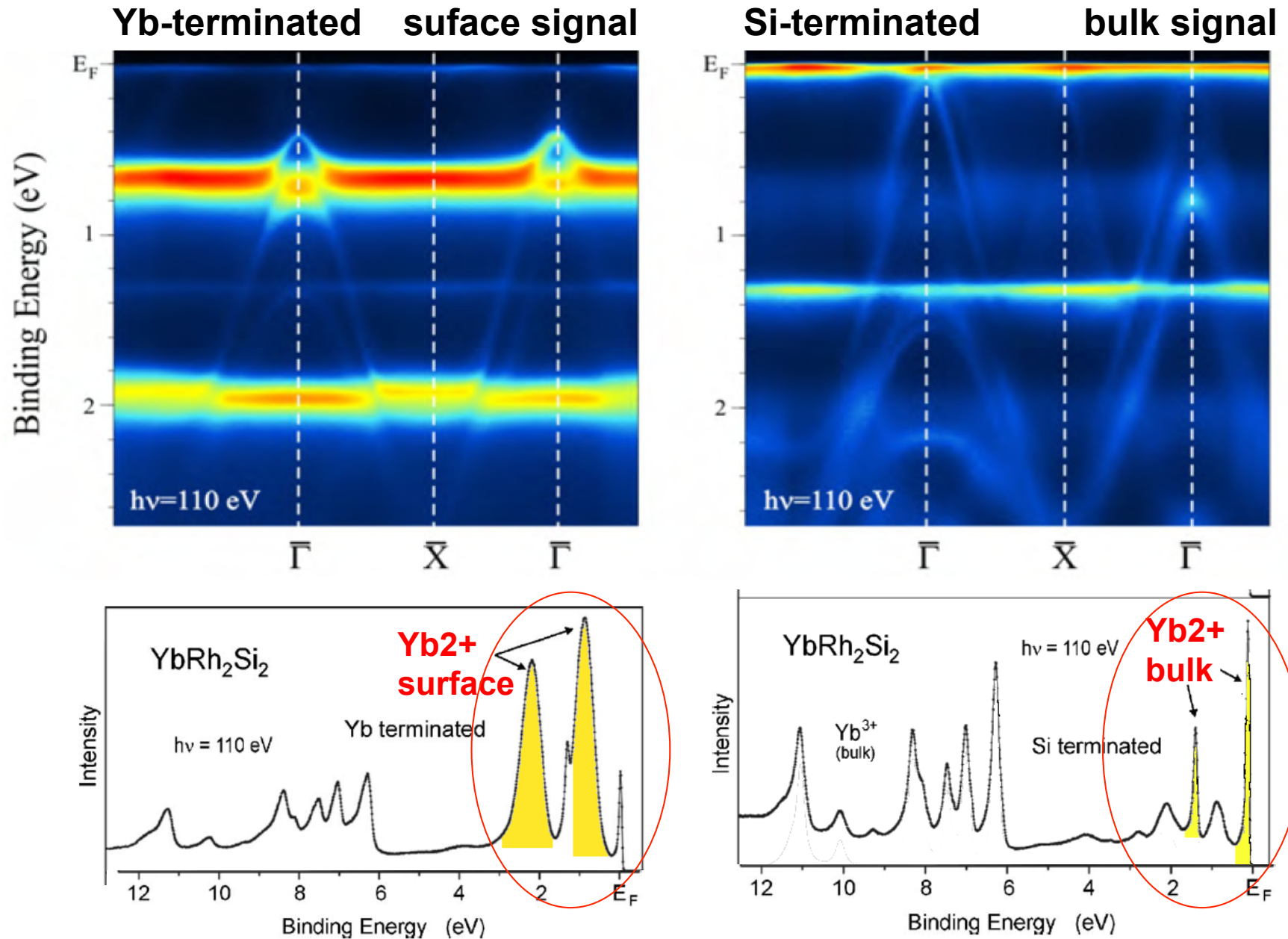
- $ThCr_2Si_2$ -structure
- Tightly bond Si-T-Si blocks  
→ cleavage between RE and Si layers
- Surface state at Si-terminated surfaces

M. Güttler et al., PRB 90,195138 (2014)



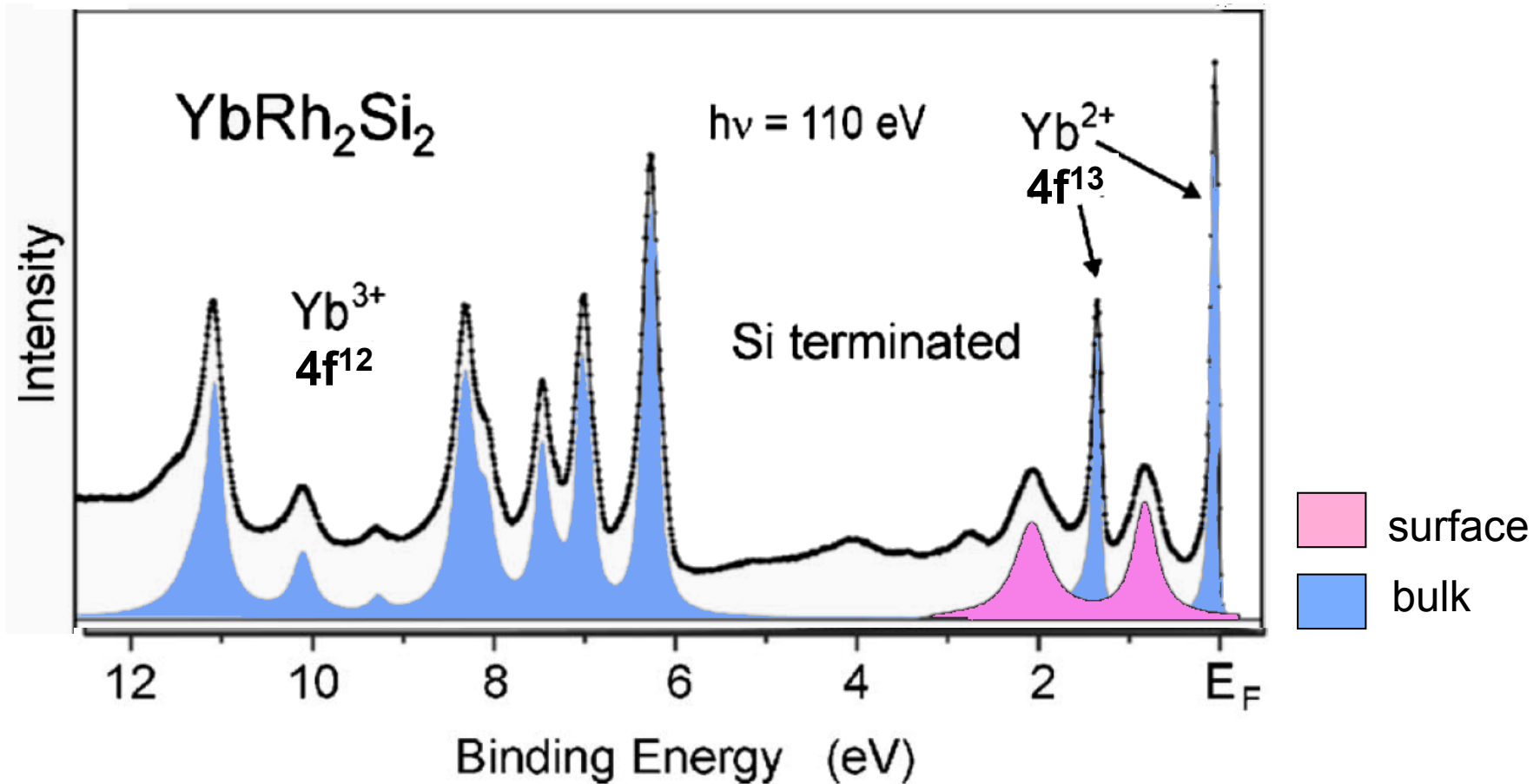


# *YbRh<sub>2</sub>Si<sub>2</sub>, mean valence ~2,9*



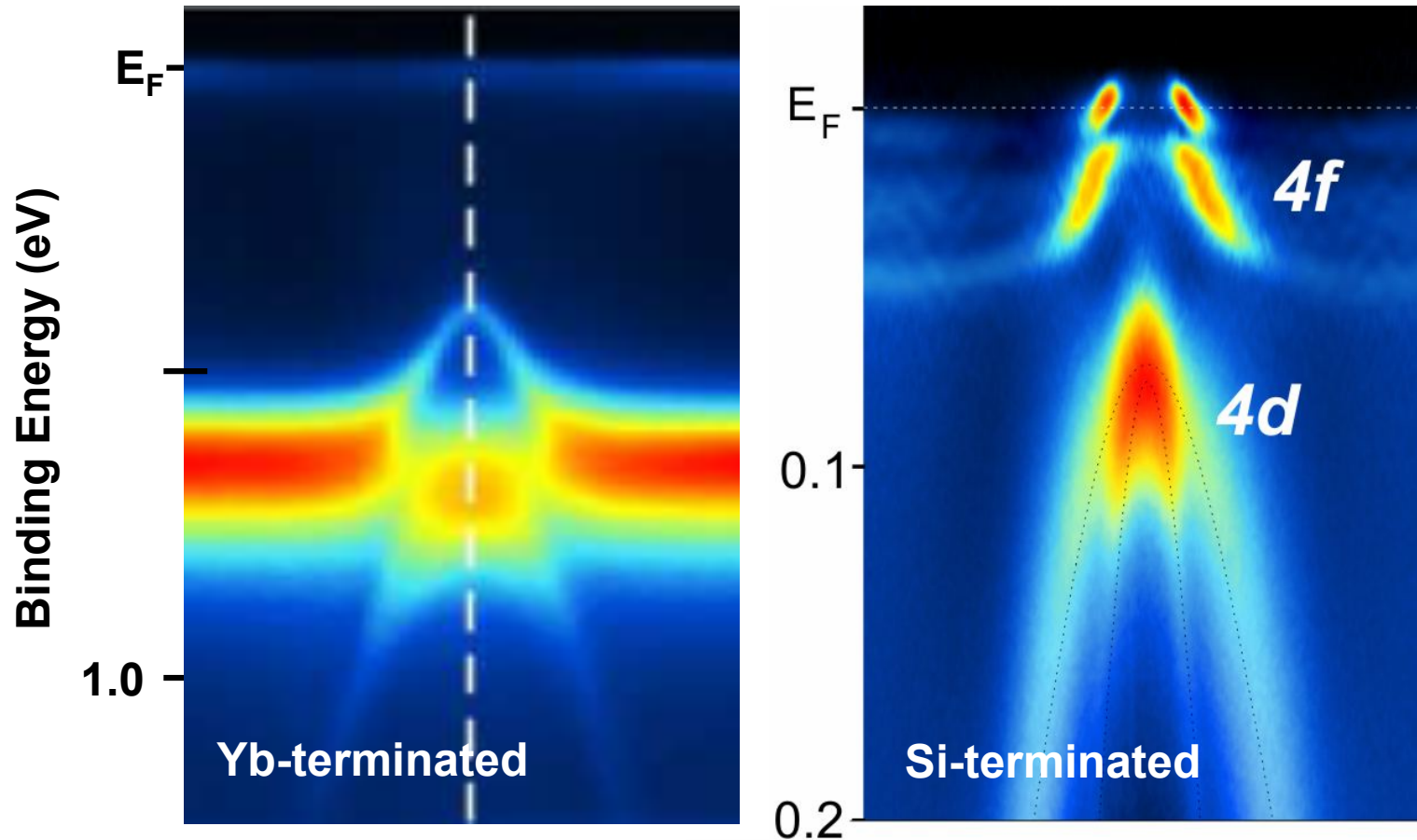
S. Danzenbächer et al., PRB 75, 45109 (2007)

# YbRh<sub>2</sub>Si<sub>2</sub>: Analysis within SIAM



- Bulk emission governed by strong 4f<sup>12</sup> final-state multiplet and weak 4f<sup>13</sup> doublet → mixed valent, valence 2,93  
SIAM-Parameter:  $\epsilon_f = 0.1 \text{ eV}$ ,  $\Delta = 0.12 \text{ eV}$ ,  $U_{ff} = 6 \text{ eV}$
- Surface emission: Purely divalent

## YbRh<sub>2</sub>Si<sub>2</sub>: Yb and Si-termination

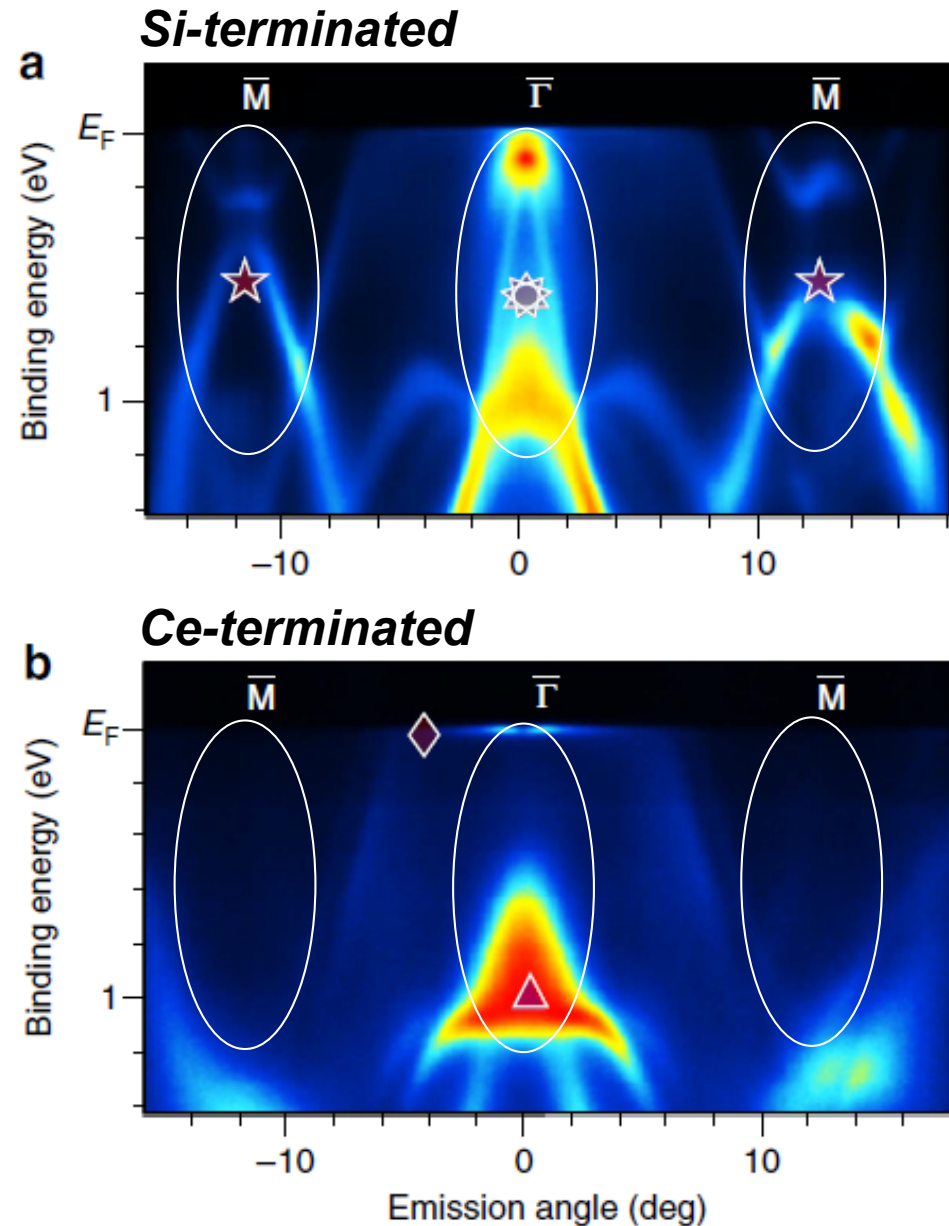


- Induced 4f-dispersion due to “avoid crossing“ of Rh-4d-band
  - Bulk: 4f crystal field splittings + 4f Fermi-level crossing → HF system
  - Yb surface: No CEF splittings and Fermi-level crossings → stable Yb<sup>2+</sup>
- D.V. Vyalikh, PRL 105, 237601 (2010)

# *CeRh<sub>2</sub>Si<sub>2</sub>: Surface termination*

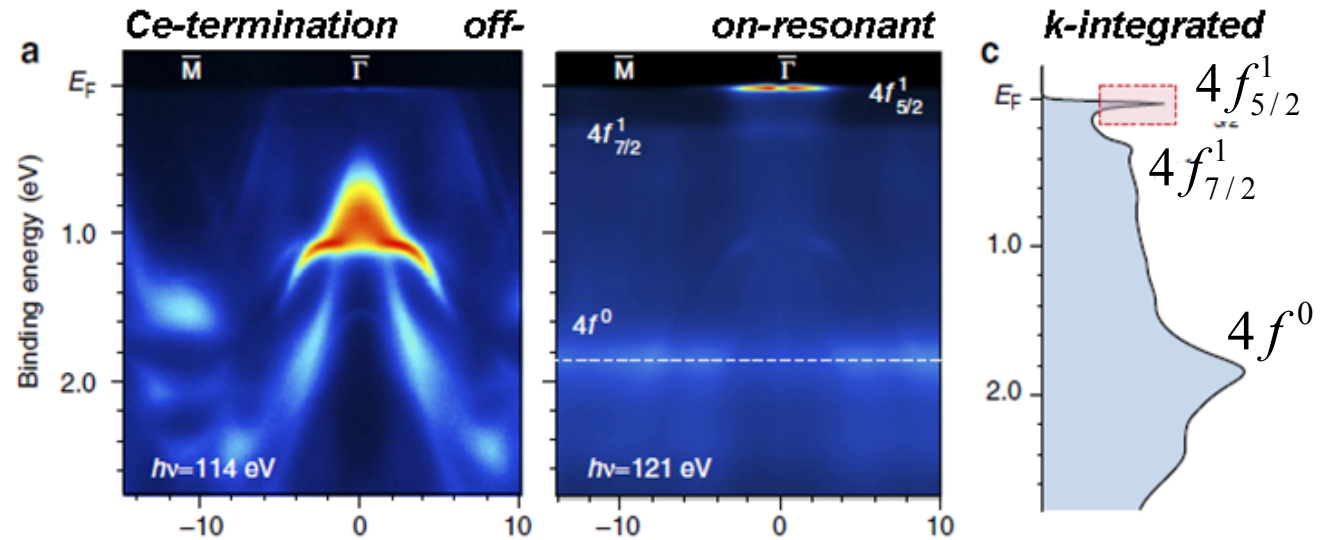
- Surface termination may be determined by watching the surface state within the large gap of the projected band-structure around the M-point (marked by star) which only exists at Si-terminated surfaces
- Also the surface resonance at the  $\Gamma$ -point (Dirac cone) is characteristic for Si-termination although there are underlying bulk bands weakly visible also at Ce termination.
- Data taken off-resonance at 112 eV photon energy

S. Patil et al., *Nature Comm.* 7, 11029 (2016)

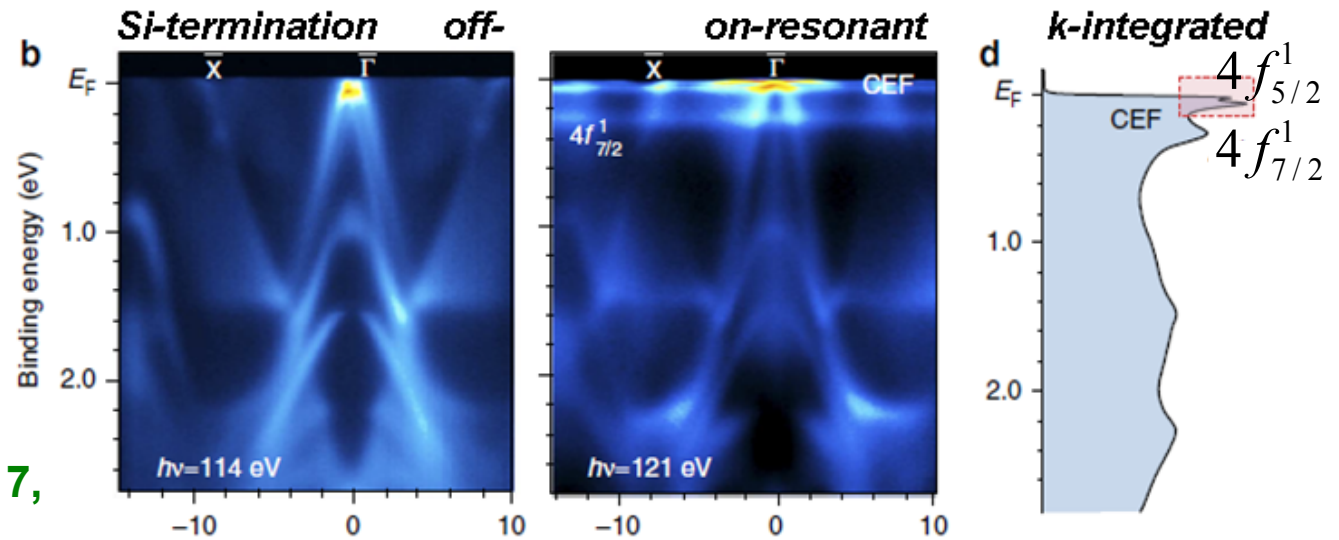


# CeRh<sub>2</sub>Si<sub>2</sub>: Bulk and surface electron structure

- **Ce at surface sites:**  
Well defined ionization peak (“4f<sup>0</sup>”),  
4f<sup>1</sup> signal only around  
Γ-point consisting almost  
of 4f<sup>1</sup><sub>5/2</sub> component at E<sub>F</sub>..  
⇒ **weakly hybridized**



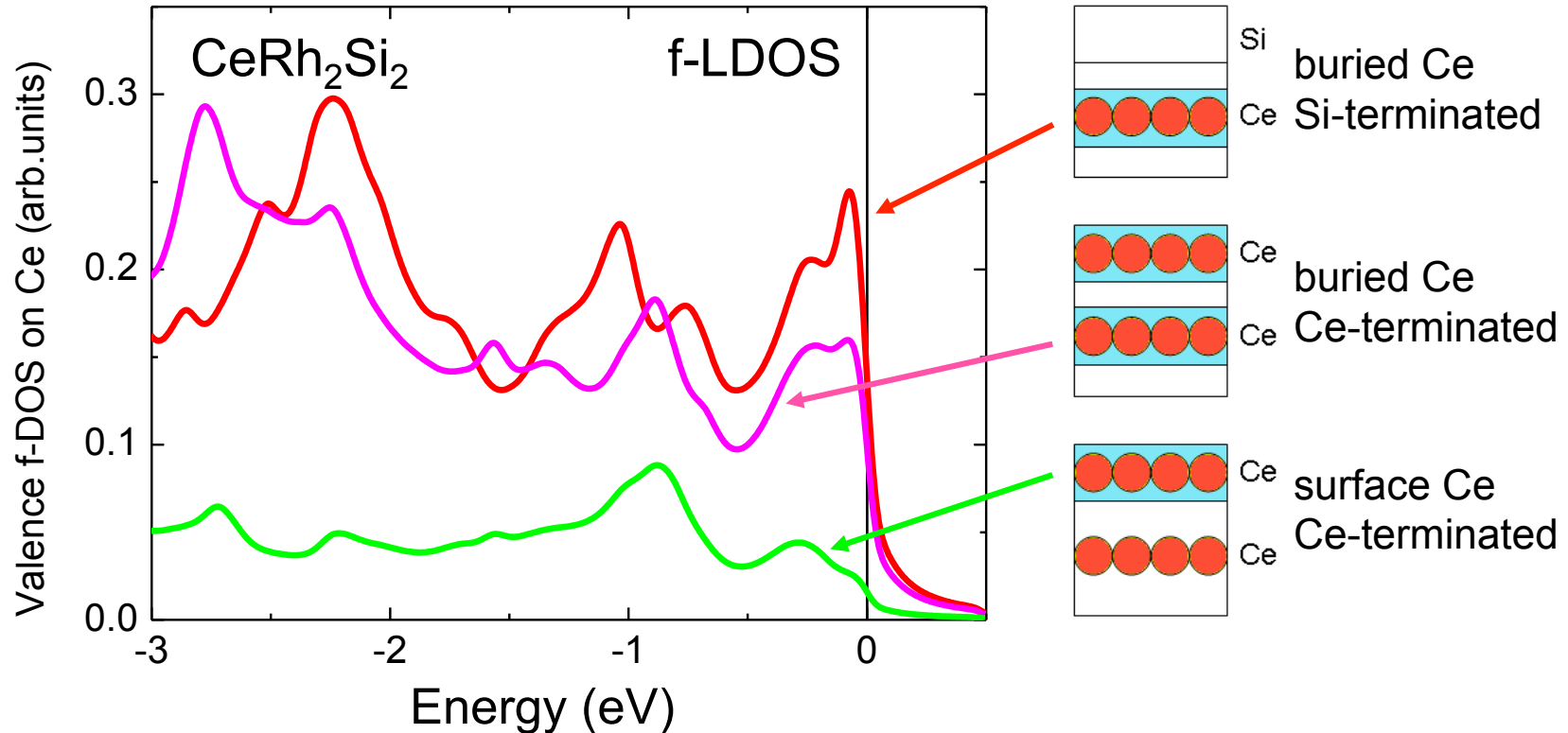
- **Ce in the bulk:**  
4f<sup>0</sup>-character fully merged  
into the valence band.  
Intense 4f<sup>1</sup><sub>5/2</sub> emission  
with crystal field splitting  
and 4f<sup>1</sup><sub>7/2</sub> side band.  
⇒ **strongly hybridized**



S. Patil et al., Nature Comm. 7, 11029 (2016)

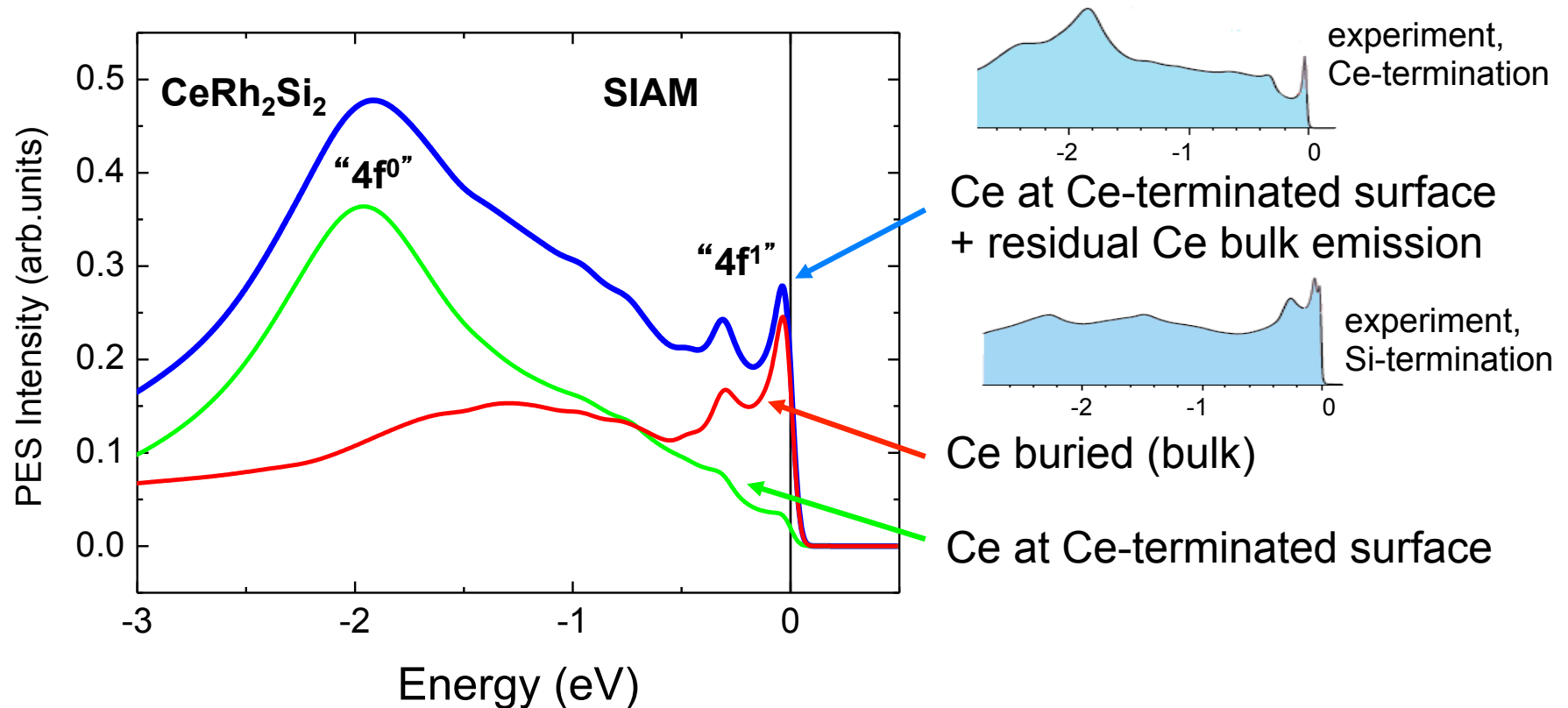


## Different hybridization in the bulk and at the surface



- hybridization  $\sim$  hopping probability  $4f \leftrightarrow$  valence band f-LDOS
- surface: coordination reduced  $\rightarrow$  hopping probability reduced
- surface: f-LDOS near  $E_F$  reduced  $\rightarrow$  hopping probability reduced
- bulk: f-LDOS large around 2 eV  $\rightarrow$  strong hybridization of  $4f^0$ -state

# Simulation within the Single-Impurity Anderson-Model

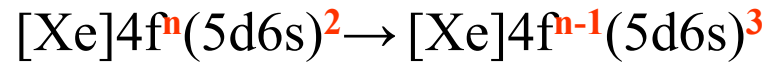


Parameter: Bulk:  $\epsilon_f = -1.7$  eV,  $\Delta = 1.05$  eV,  $U_{ff} = 6$  eV.  
 Surface:  $\epsilon_f = -1.9$  eV,  $\Delta = 0.7$  eV (70% from bulk),

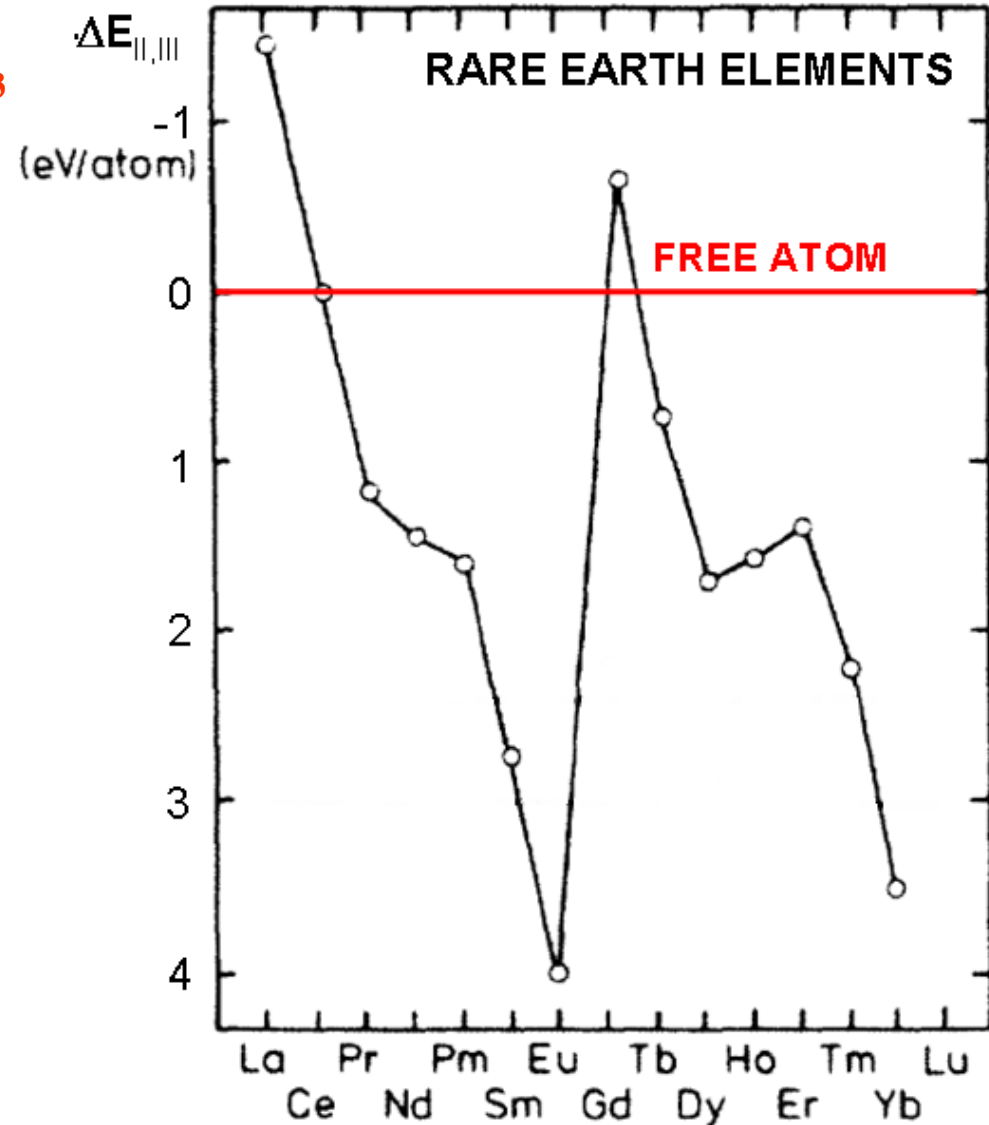
- strong "4f<sup>1</sup>"-signal for bulk Ce, shift and smearing of weak "4f<sup>0</sup>" component
- weak "4f<sup>1</sup>"-signal for Ce at surface, well pronounced "4f<sup>0</sup>" component

# Thermochemical model: Valence of rare-earth elements

$\Delta E_{II,III}$  : free atom excitation energy



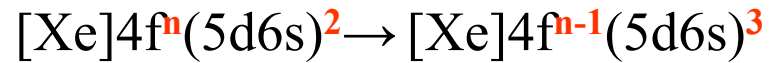
$\Rightarrow$  all rare-earths except La, Gd, Lu  
are divalent in the gas phase



B. Johansson, Phys. Rev. B20, 1315 (1979)

## Valence of rare-earth elements

$\Delta E_{II,III}$  : free atom excitation energy



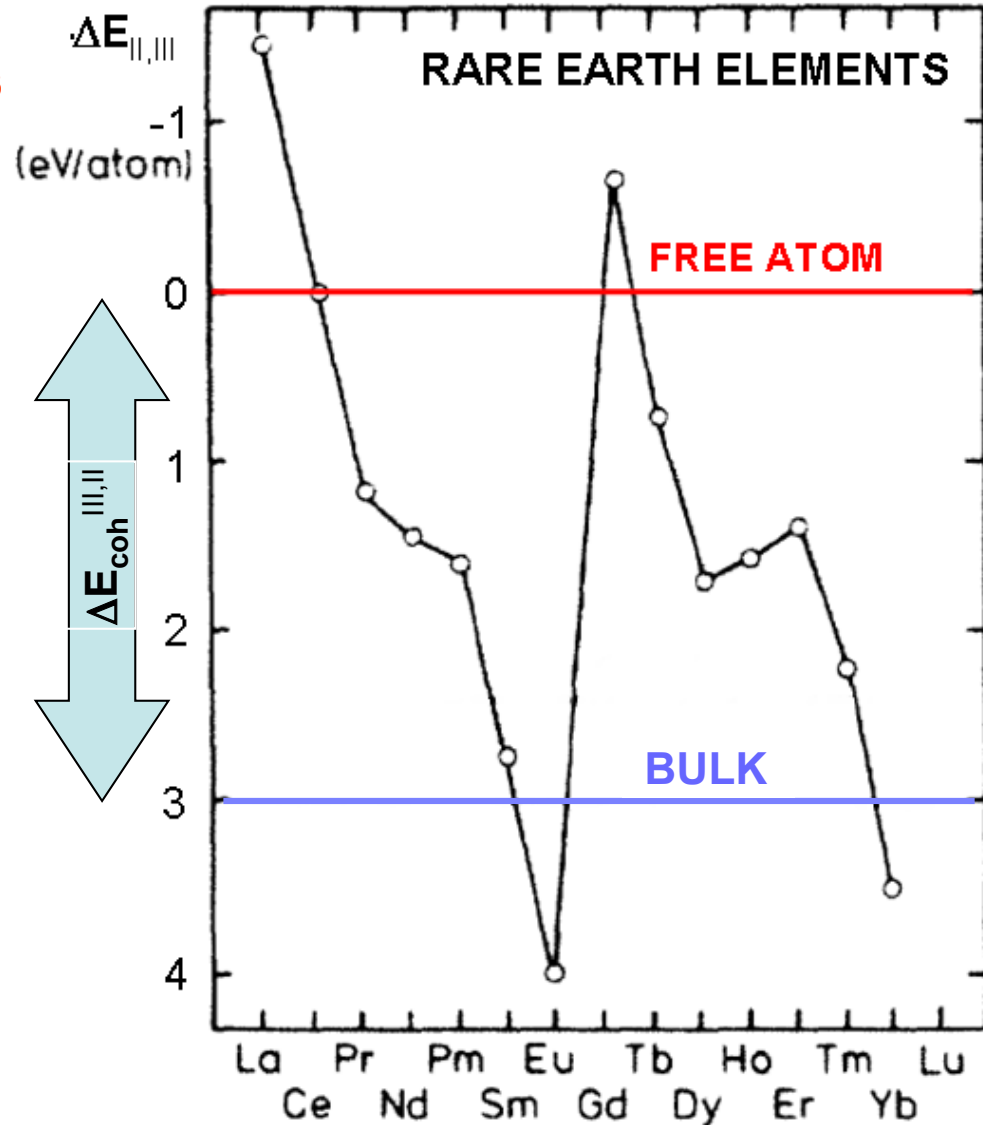
$\Rightarrow$  all rare-earths except La, Gd, Lu  
are divalent in the gas phase

Metals: Gain in cohesive energy

$$\Delta E_{\text{coh}}^{II,III} = E_{\text{coh}}^{III} - E_{\text{coh}}^{II}$$

$\Rightarrow$  “zero line” shifts downwards

$\Rightarrow$  only Eu, Yb remain divalent

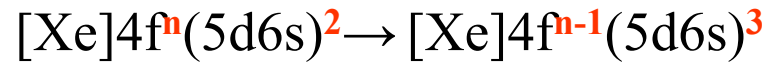


B. Johansson, Phys. Rev. B20, 1315 (1979)



# Valence of rare-earth elements

$\Delta E_{II,III}$  : Free atom excitation energy



⇒ all rare-earths except La, Gd, Lu  
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$$\Delta E_{\text{coh}}^{II,III} = E_{\text{coh}}^{III} - E_{\text{coh}}^{II}$$

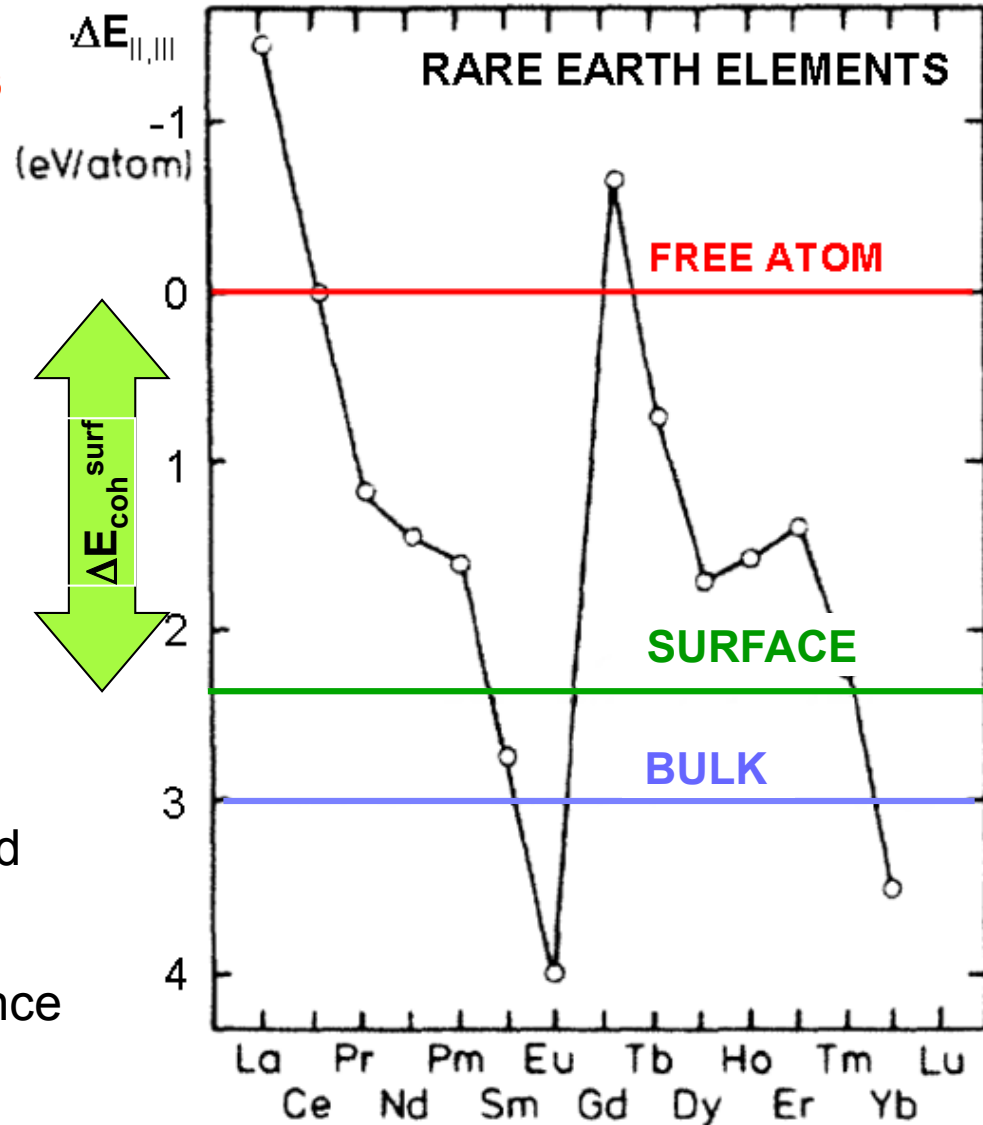
⇒ “zero line” shifts downwards

⇒ only Eu, Yb remain divalent

Surfaces: Cohesive Energy reduced

$$\Delta E_{\text{coh}}^{\text{surf}} \approx 0,8 \cdot \Delta E_{\text{coh}}^{\text{bulk}}$$

⇒ Sm-metal reveals “surface valence transition” to divalent state



**B. Johansson, Phys. Rev. B20, 1315 (1979)**

# Photoemission of 4f-states

Divalent systems:

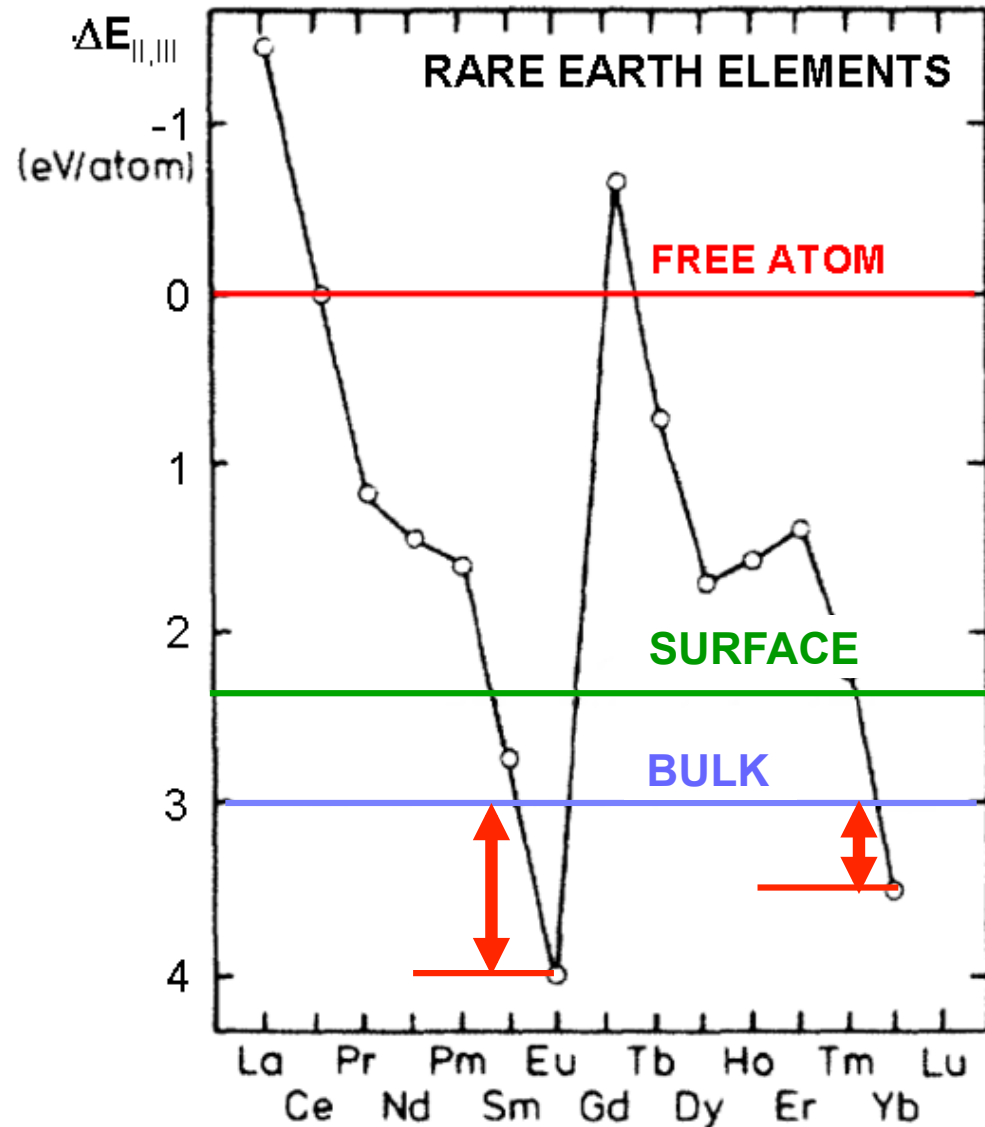
Fully screened final state

$$E_{\text{BIN}} = \Delta E_{\text{II,III}} + E_{\text{IMP}}$$

“Impurity term” considers that not the whole system undergoes valence transition

pure metals:  $E_{\text{IMP}} \approx 0.6 \text{ eV}$

compounds:  $E_{\text{IMP}} \approx 0,1 \text{ eV}$



B. Johansson, Phys. Rev. B20, 1315 (1979)

# Photoemission of 4f-states

Divalent systems:

Fully screened final state

$$E_{\text{BIN}} = \Delta E_{\text{II,III}} + E_{\text{IMP}}$$

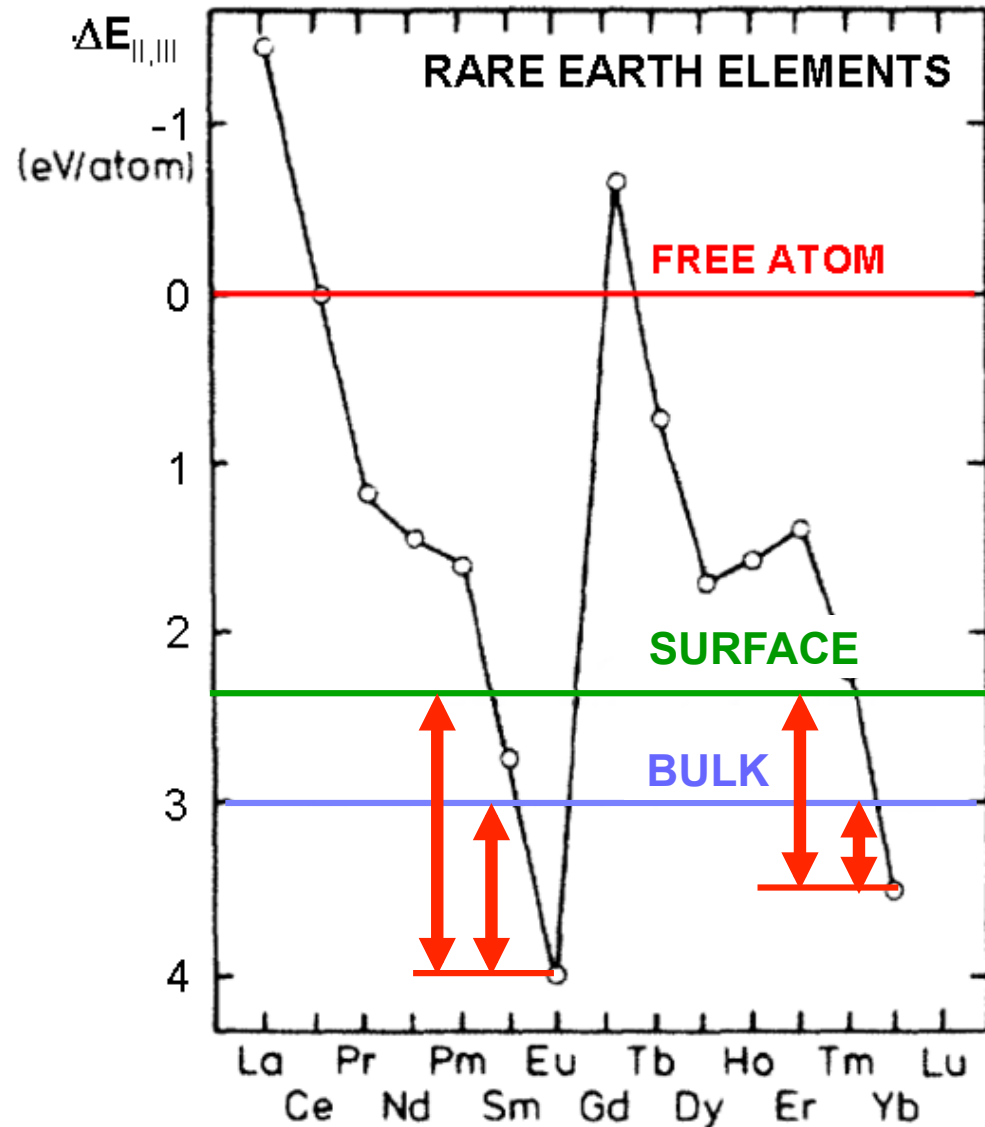
“Impurity term” considers that not the whole system undergoes valence transition

pure metals:  $E_{\text{IMP}} \approx 0.6 \text{ eV}$

compounds:  $E_{\text{IMP}} \approx 0,1 \text{ eV}$

At surfaces  $E_{\text{BIN}}$  larger:

“surface core-level shift”



B. Johansson, Phys. Rev. B20, 1315 (1979)

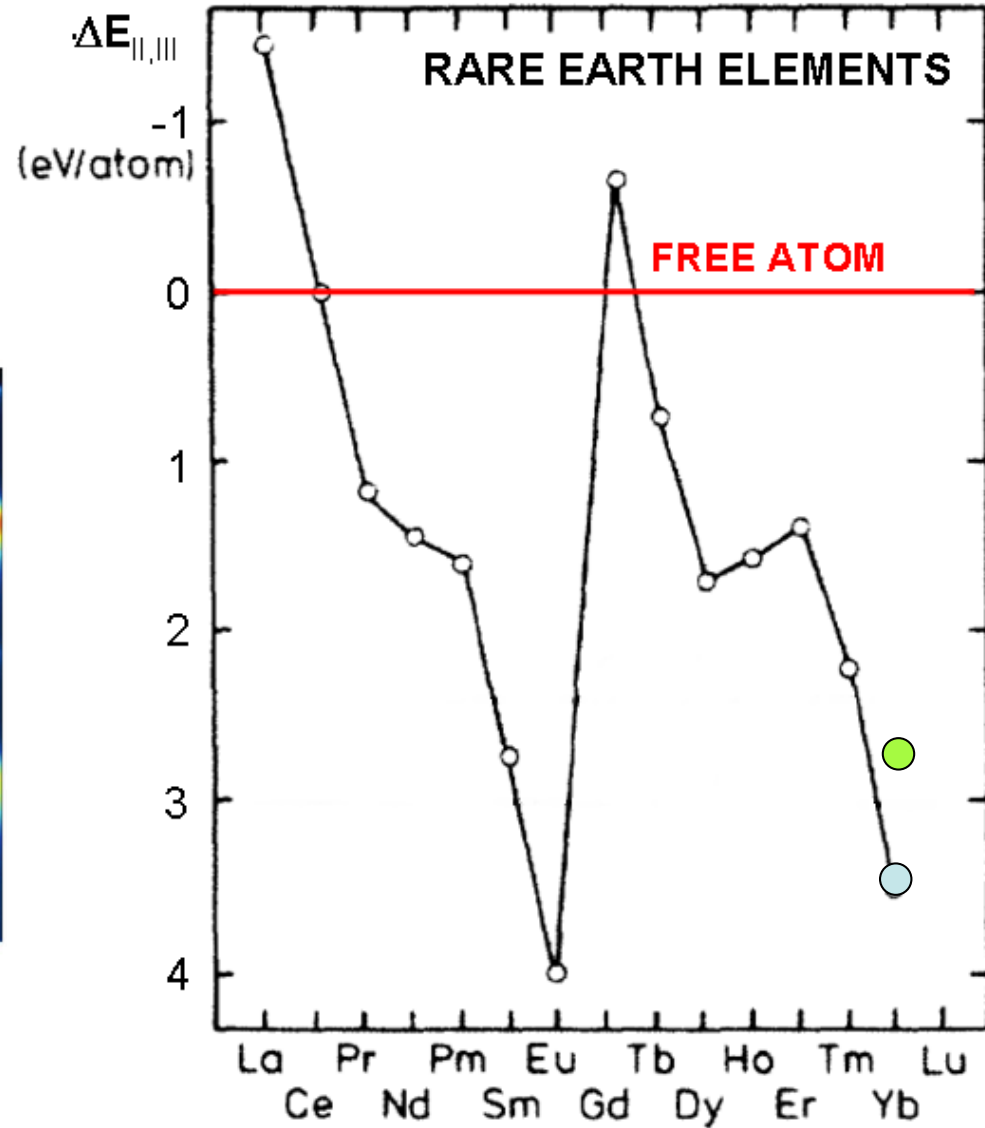
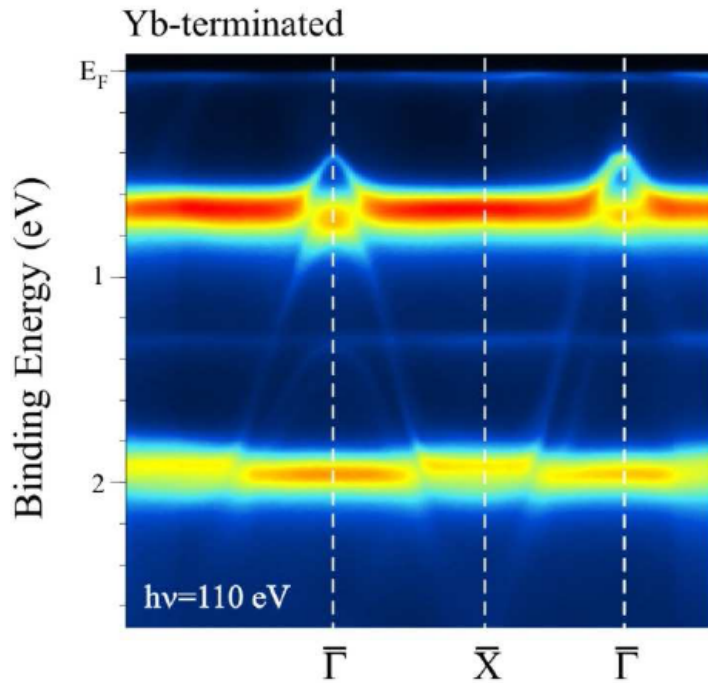
# Photoemission of 4f-states

RERh<sub>2</sub>Si<sub>2</sub> compounds:

RE = Yb: mixed-valent

$$E_{\text{BIN}} \approx 0 \text{ eV,}$$

$$E_{\text{BIN}}^{\text{surf}} \approx 0,7 \text{ eV}$$





# Photoemission of 4f-states

RERh<sub>2</sub>Si<sub>2</sub> compounds:

RE = Yb: mixed-valent

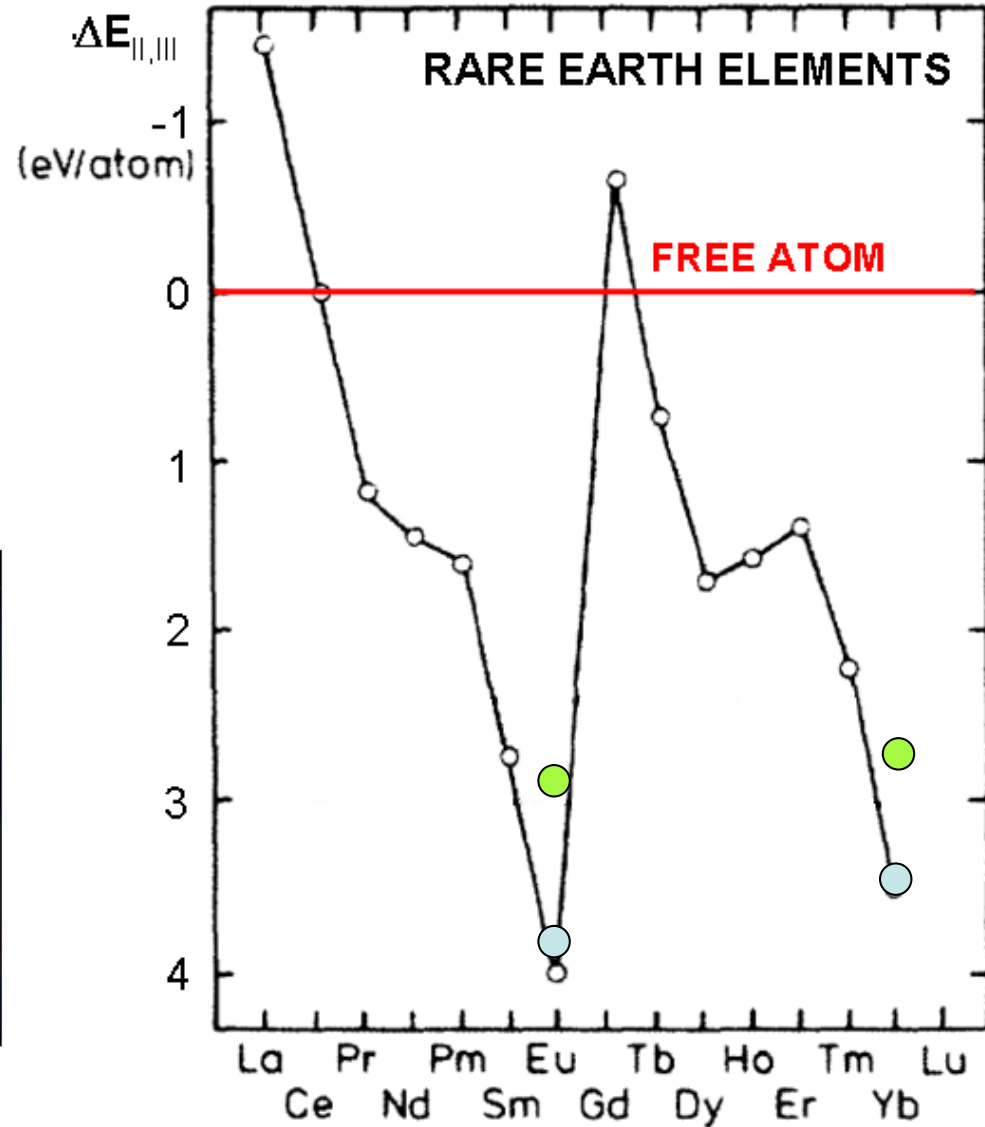
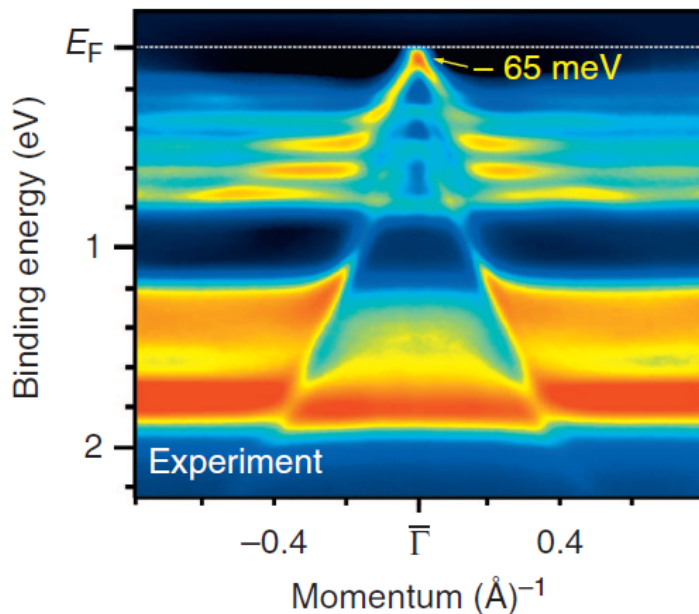
$$E_{\text{BIN}} \approx 0 \text{ eV,}$$

$$E_{\text{BIN}}^{\text{surf}} \approx 0,7 \text{ eV}$$

RE = Eu: divalent

$$E_{\text{BIN}} \approx 0,2 \text{ eV,}$$

$$E_{\text{BIN}}^{\text{surf}} \approx 1,0 \text{ eV}$$



# Photoemission of 4f-states

RERh<sub>2</sub>Si<sub>2</sub> compounds:

RE = Yb: mixed-valent

$$E_{\text{BIN}} \approx 0 \text{ eV,}$$

$$E_{\text{BIN}}^{\text{surf}} \approx 0,7 \text{ eV}$$

RE = Eu: divalent

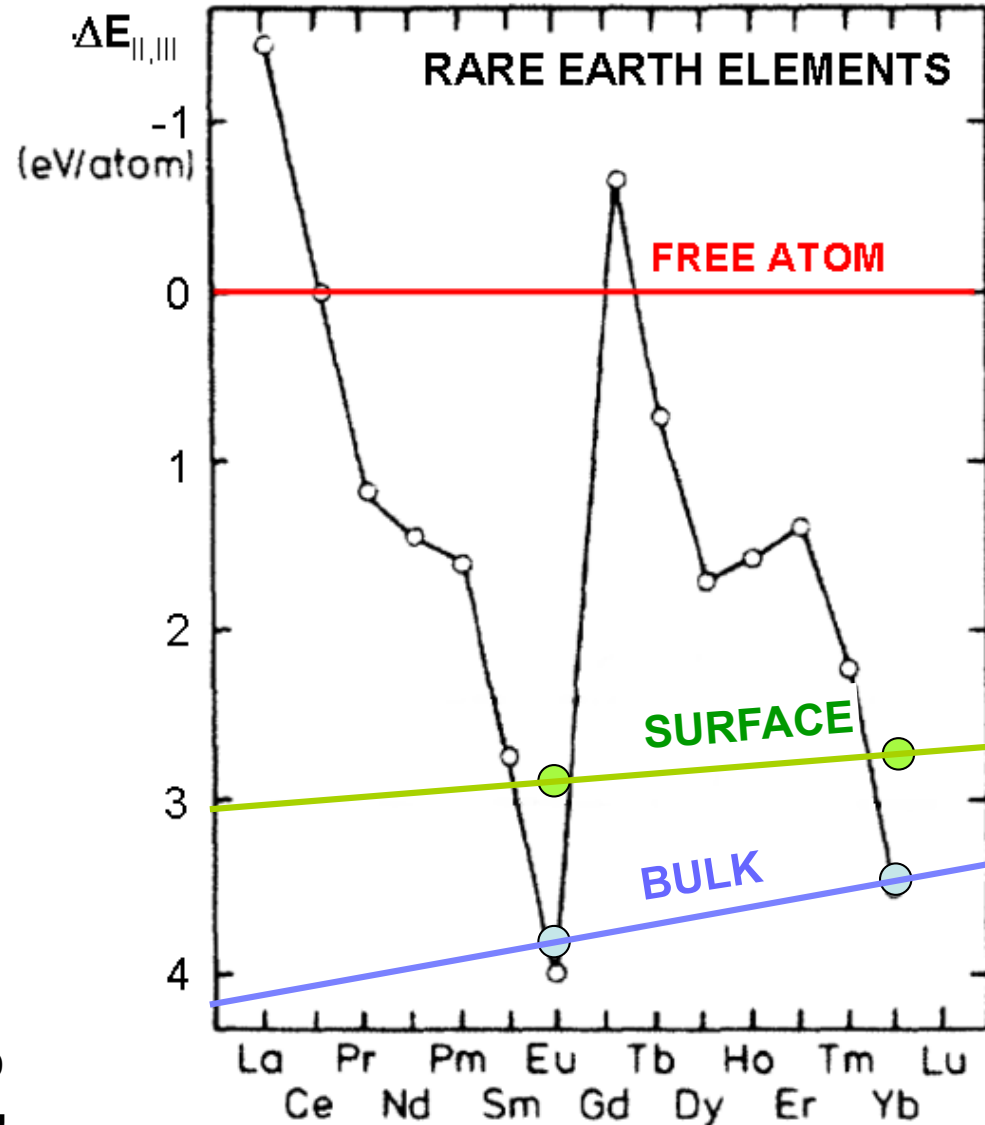
$$E_{\text{BIN}} \approx 0,2 \text{ eV,}$$

$$E_{\text{BIN}}^{\text{surf}} \approx 1,0 \text{ eV}$$

Prediction for whole series:

All RE except Eu, Yb  
trivalent in the bulk  
and at the surface!

Inclination of lines due to  
different atomic volumes!



# Photoemission of 4f-states

RERh<sub>2</sub>Si<sub>2</sub> compounds:

RE = Yb: mixed-valent

$$E_{\text{BIN}} \approx 0 \text{ eV,}$$

$$E_{\text{BIN}}^{\text{surf}} \approx 0,7 \text{ eV}$$

RE = Eu: divalent

$$E_{\text{BIN}} \approx 0,2 \text{ eV,}$$

$$E_{\text{BIN}}^{\text{surf}} \approx 1,0 \text{ eV}$$

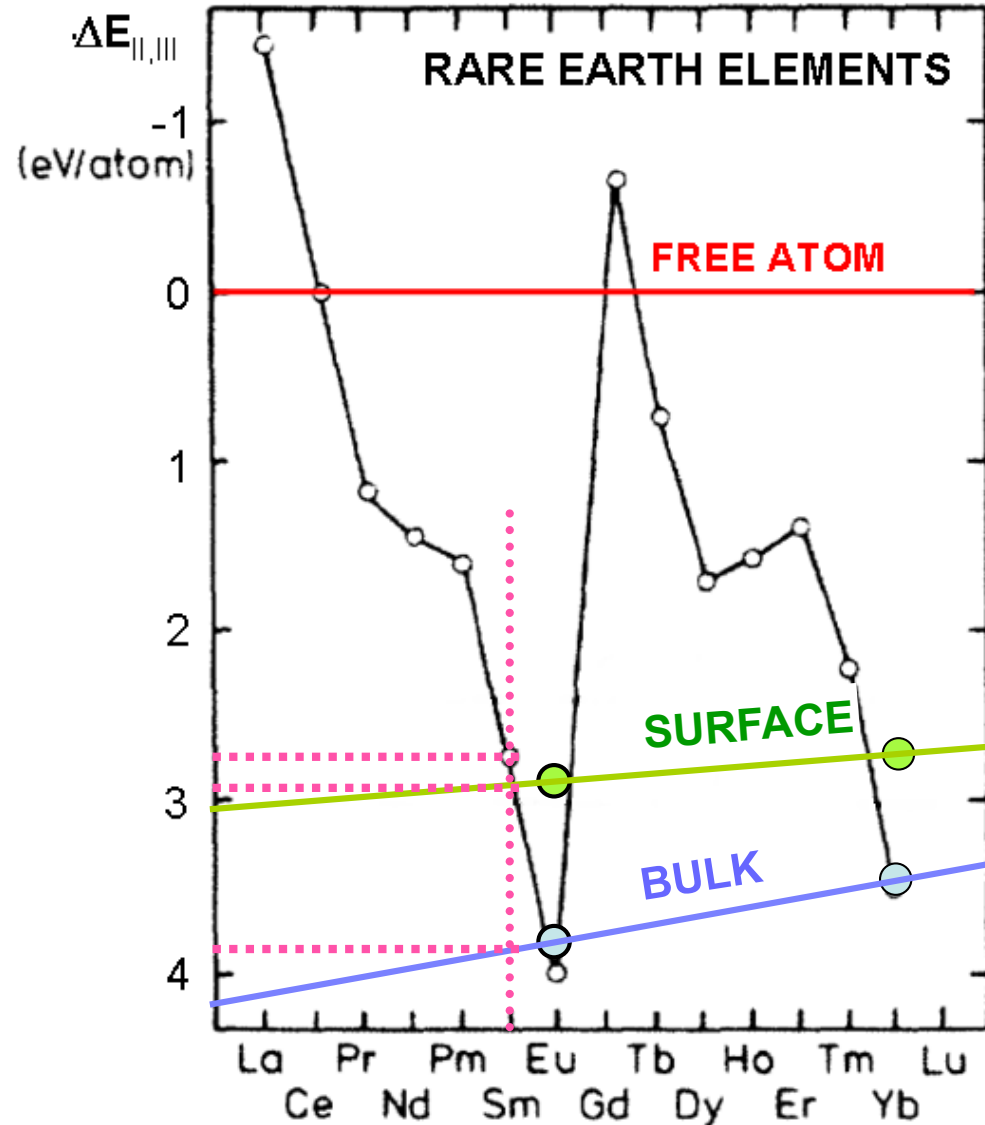
Prediction for whole series:

All RE except Eu, Yb  
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and at the surface!

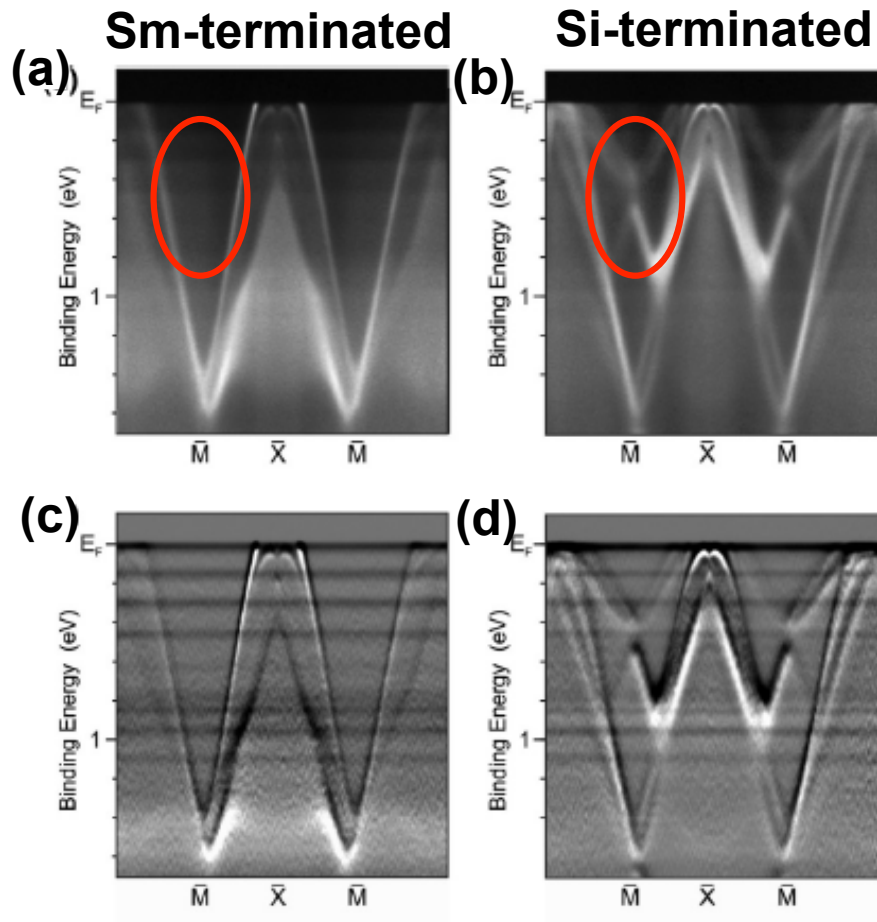
RE = Sm;  $E_{\text{BIN}} \approx -1,1 \text{ eV}$

$$E_{\text{BIN}}^{\text{surf}} \approx -0,2 \text{ eV}$$

Trivalent in the bulk  
and at the surface



# $SmRh_2Si_2$

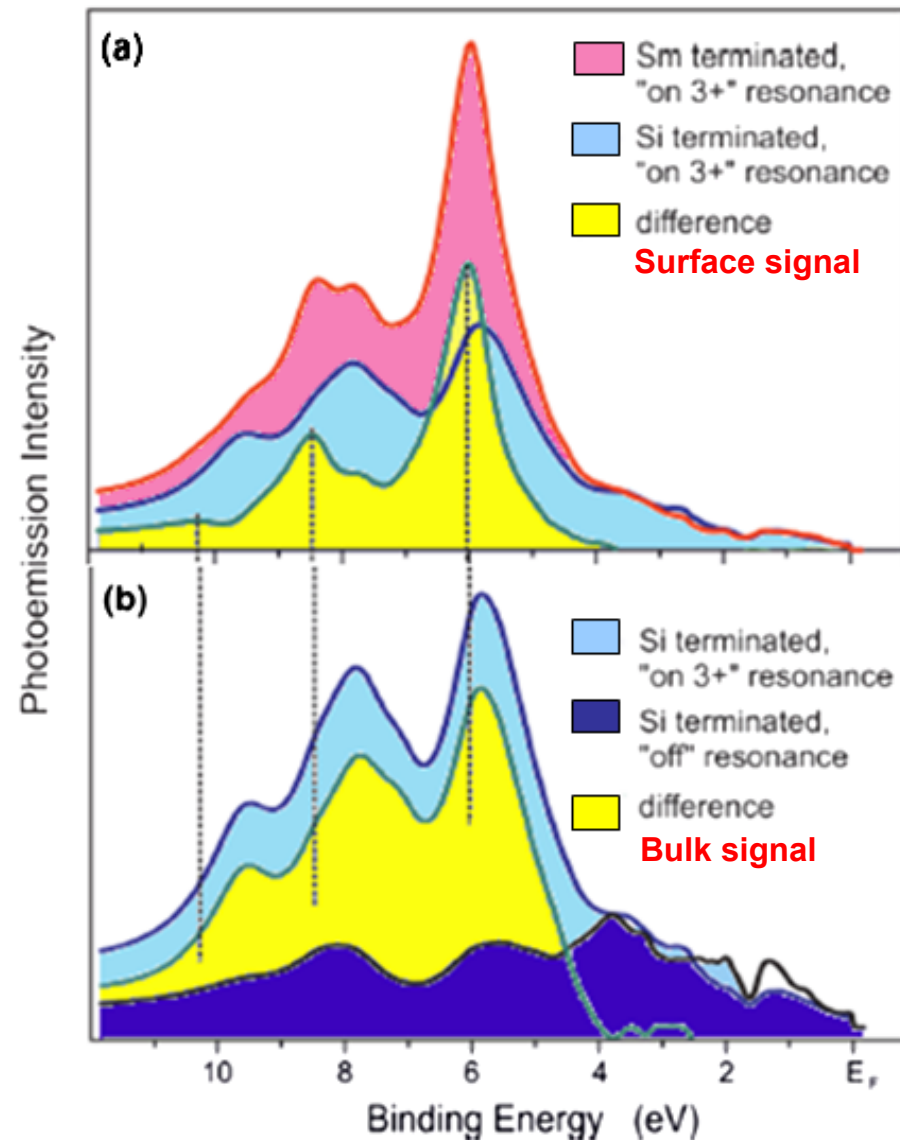
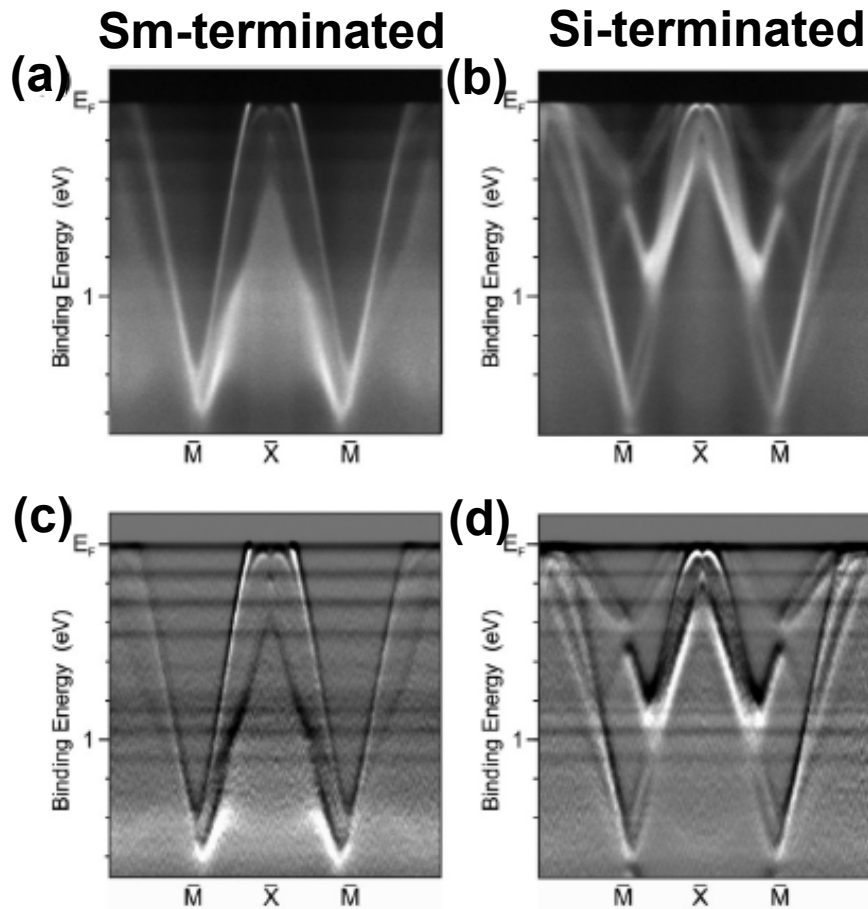


- Si-termination identified by surface state around M-point

A. Chikina et al., PRB 95, 155127 (2017)

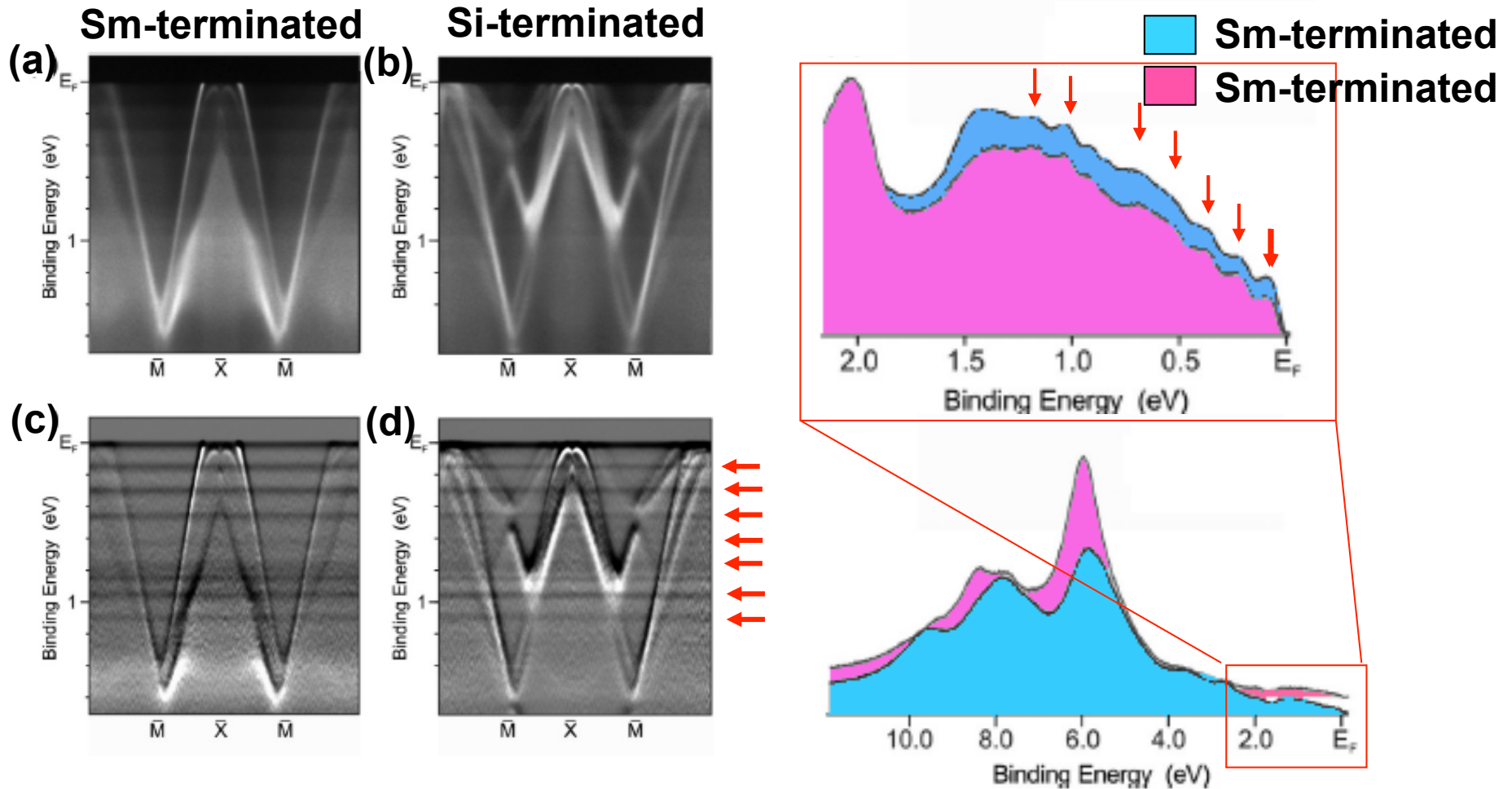


# SmRh<sub>2</sub>Si<sub>2</sub>



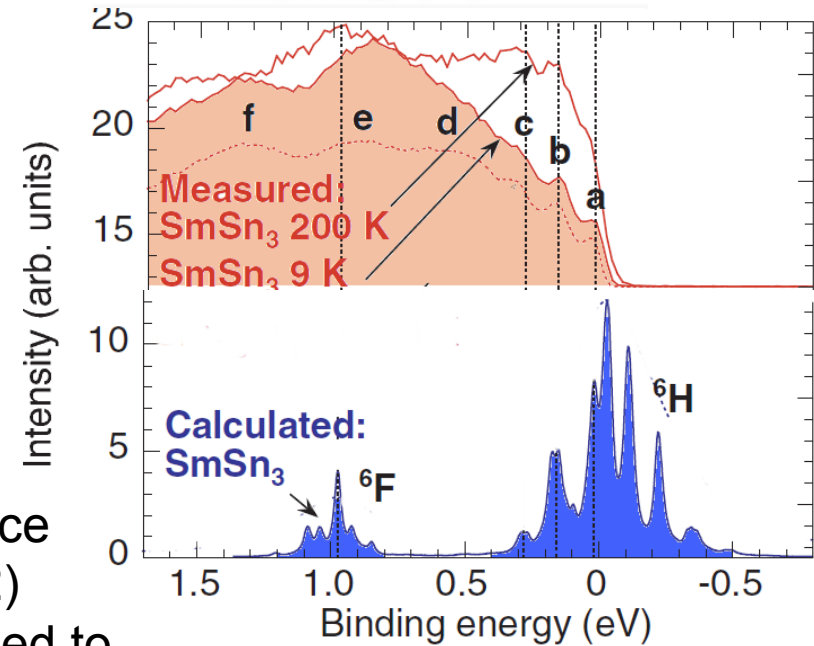
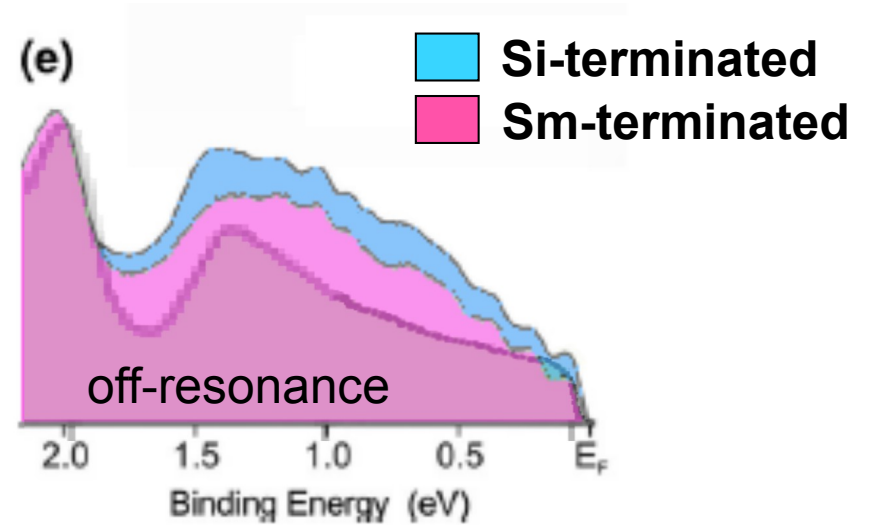
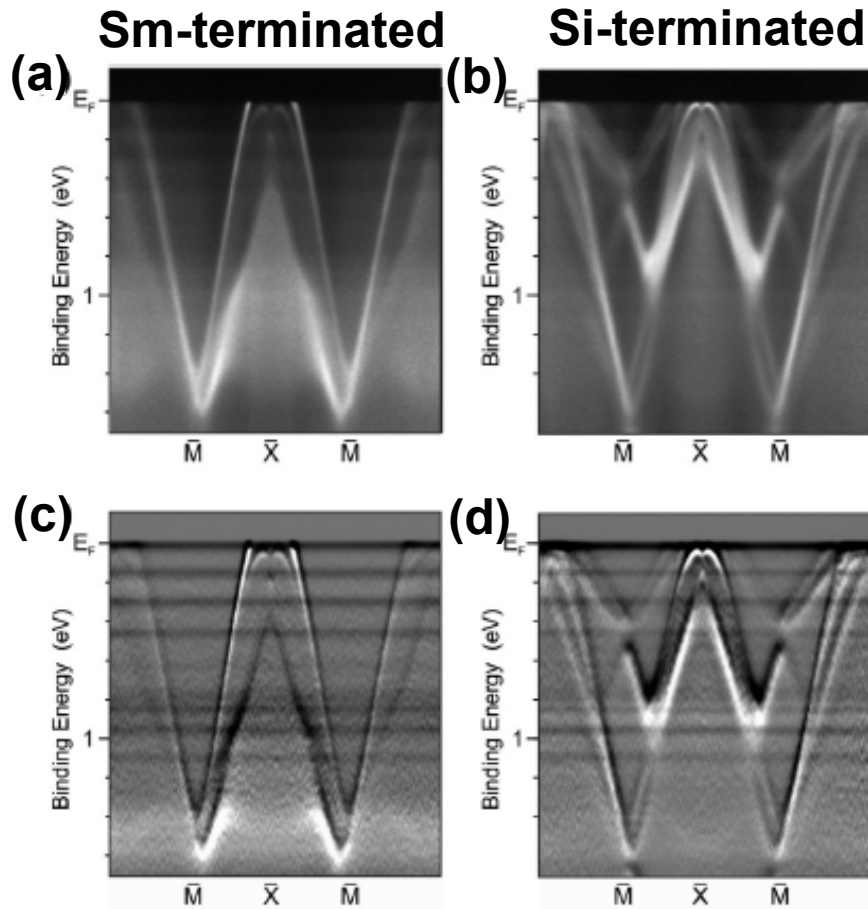
- Si-termination identified by surface state around M-point
- Bulk and surface spectra dominated by 4f<sup>4</sup> multiplets
- Clear surface-shift of 4f<sup>4</sup> multiplet → **almost trivalent in the bulk and at the surface**  
Bulk signal broadened by hybridization, surface shift 0.3-1.0 eV

# $SmRh_2Si_2$



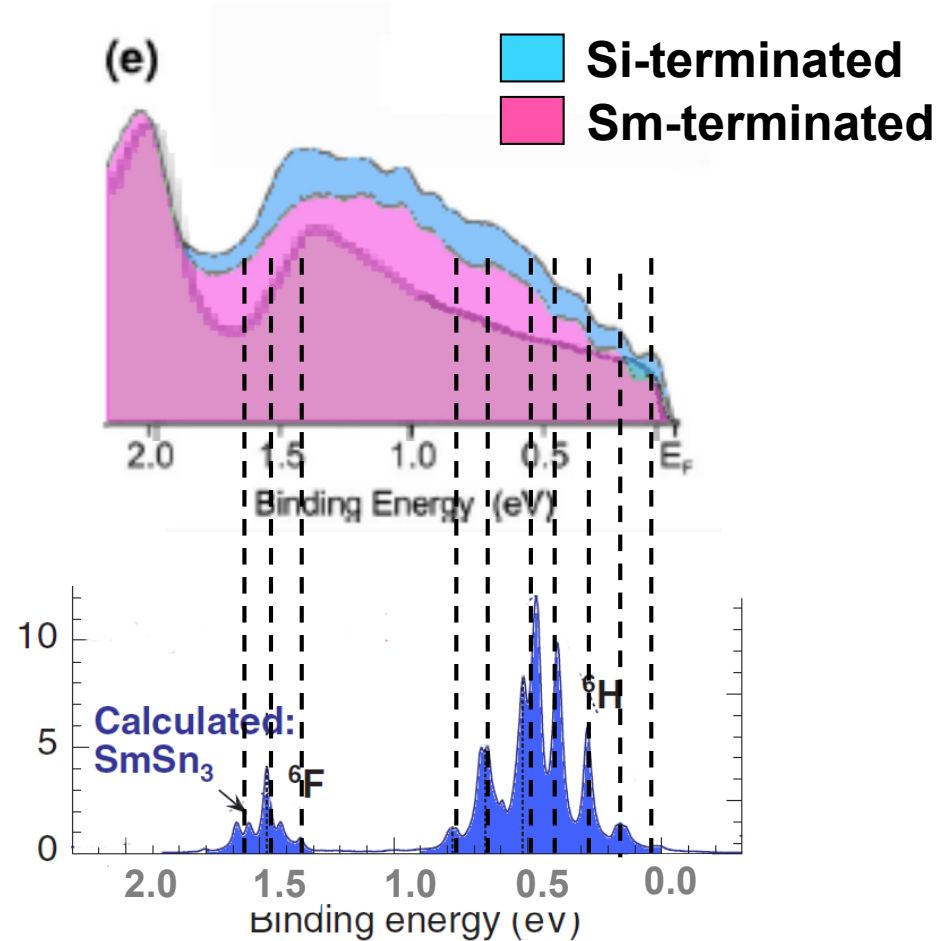
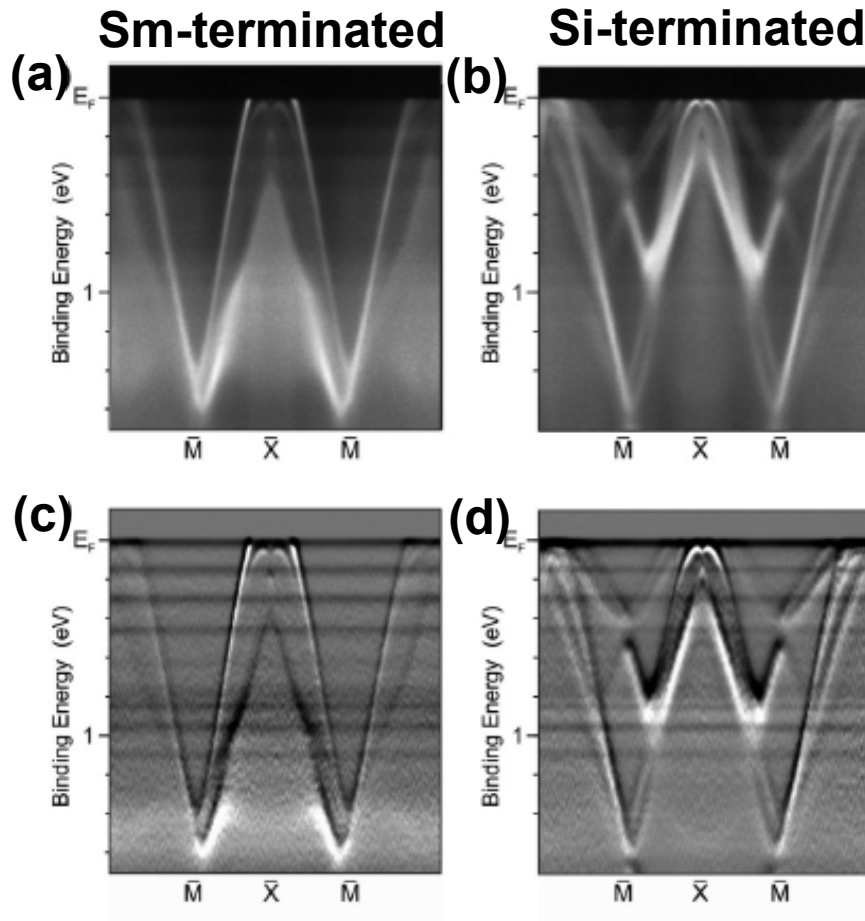
- Si-termination identified by surface state around M-point
- Bulk and surface spectra dominated by  $4f^4$  multiplet
- Clear surface-shift of  $4f^4$  multiplet  $\rightarrow$  almost trivalent in the bulk and at the surface
- Non-dispersive stripe-structure near  $E_F$   $\rightarrow$  additional  $4f^5$  multiplet?

# $SmRh_2Si_2$



- Spectral shape similar for bulk and surface
- H. Yamaoka et al, PRB **85**, 115120 (2012)
- Similar stripes observed in  $SmSn_3$  assigned to **shifted  $4f^5$  multiplet**

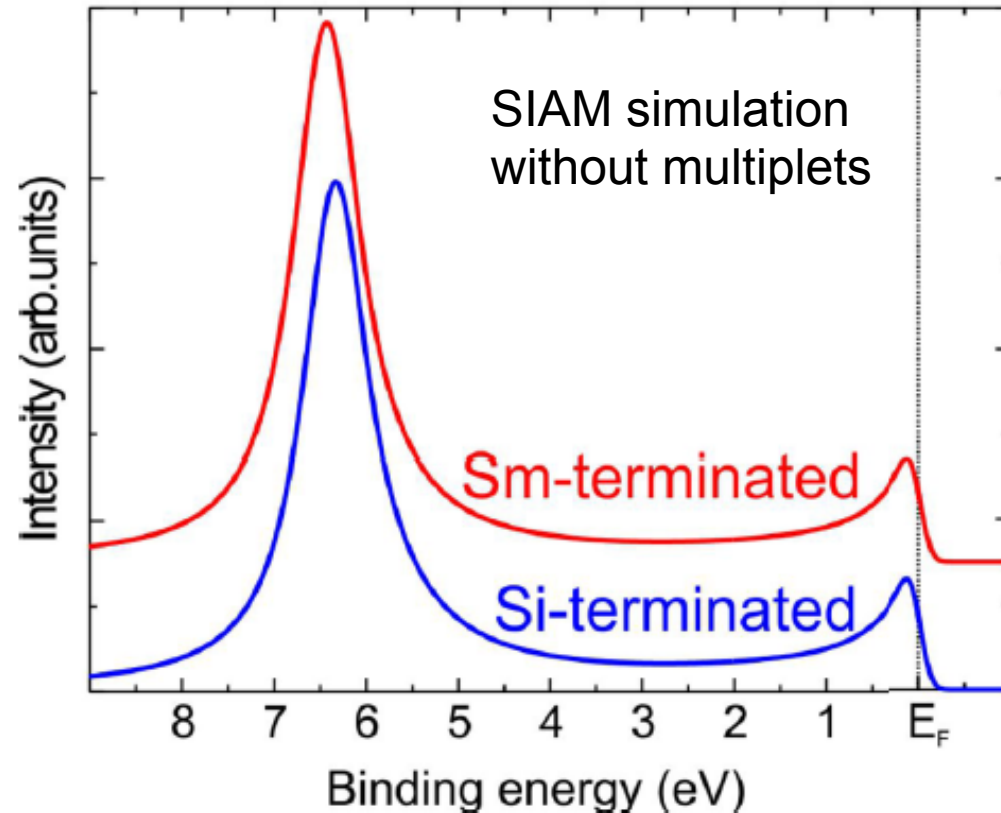
# SmRh<sub>2</sub>Si<sub>2</sub>



- For mixed-valent Sm 4f<sup>5</sup>-multiplet must be pinned at E<sub>F</sub> both for bulk and surface
- Intensity of individual multiplet terms may be altered due to resonance
- **Mixed-valent in the bulk and at the surface** with mean valence around 2.9

# Sm-valence in $\text{SmRh}_2\text{Si}_2$ : SIAM

- Neglect of multiplet effects and double-excitations
- Estimation of  $\Delta$ -parameter from interpolation between Ce- and Yb-system  
Bulk:  $\Delta = 0.7$  eV
- Assumption: Reduction of  $\Delta$  at surface to 70% of bulk value
- Setting  $\varepsilon = -E_{\text{BIN}}(4f^4)$   
Bulk:  $\varepsilon = -6.0$  eV  
Surface:  $\varepsilon = -6.3$  eV
- With  $U_{\text{ff}} = 7$  eV from LDA+U we get for  $-E_{\text{BIN}}(4f^5) \approx \varepsilon + U_{\text{ff}}$   
Bulk:  $E_{\text{BIN}} = -1.0$  eV (-1.1 eV)  
Surf:  $E_{\text{BIN}} = -0.7$  eV (-0.3 eV)  
thermochemical estimate in parenthesis



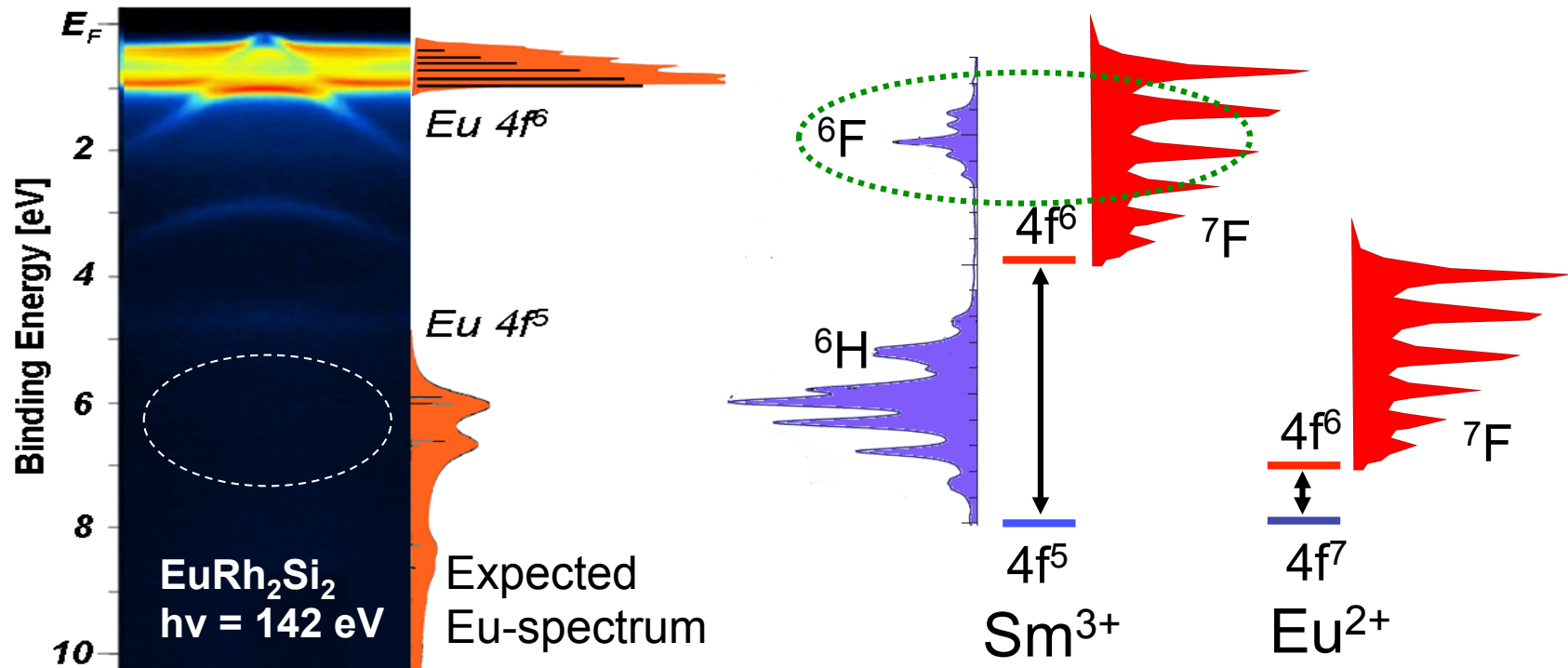
## Result of SIAM:

**Bulk: mean Sm-valence: 2.94**  
**Surface: mean Sm-valence: 2.95**  
**Behavior qualitatively similar to Ce!**



# Why is $\text{EuRh}_2\text{Si}_2$ stable divalent?

- Assuming for **Eu similar  $\Delta$  as for Sm** and  $\varepsilon = 0.2$  eV  
 →  **$\text{EuRh}_2\text{Si}_2$  should be mixed-valent, mean valence  $\sim 2.5$ !**
- Photoemission: **No trace of  $4f^5$  final-state** multiplet characteristic for  $\text{Eu}^{3+}$



- Hopping directly or via virtual low-energy excitations of  $4f^n$ -configurations
- Sm: Strong overlap of  $4f^5$   $6F$  and  $4f^6$   $7F$  terms
- Eu: No low-energy excitations possible in  $4f^7$  (spin-flip requires  $\Delta E > 4$  eV)  
 → hybridization strongly reduced! **A. Chikina et al., PRB 95, 155127 (2017)**



## Summary:

- clear determination of surface termination by inspection of surface state characteristic for Si-termination
- different degree of 4f-hybridization in the bulk and at the surface:  
YbRh<sub>2</sub>Si<sub>2</sub>: bulk intermediate valent close Yb<sup>3+</sup>, surface stable divalent  
CeRh<sub>2</sub>Si<sub>2</sub>: strongly hybridized in the bulk, weakly at the surface
- estimation of surface valence by means of thermochemical model  
SmRh<sub>2</sub>Si<sub>2</sub>: bulk and surface intermediate valent close to Sm<sup>3+</sup>
  - explanation within SIAM in analogy to Ce-compounds
  - possible Kondo-phenomena in Sm-compounds ?  
EuRh<sub>2</sub>Si<sub>2</sub>: bulk and surface stable divalent, although mixed-valence expected from analogy to Sm-compound
  - strongly reduced hybridization due to lacking low-energy multiplet ?
  - phenomenon generally encountered in Eu-compounds, where in contrast to weak T-dependent valence changes in Yb and Ce-systems strong abrupt 1<sup>st</sup>-order transitions take place upon T or p-changes